



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Martin Calibration, Inc.

11965 12th Avenue South

Burnsville, MN 55337

Including satellite locations located in: Mundelein, IL and Eau Claire, WI

Fulfills the requirements of

ISO/IEC 17025:2017

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

In the fields of

CALIBRATION and DIMENSIONAL MEASUREMENT

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to be 'Jason Stine', is written over a horizontal line.

Jason Stine, Vice President

Expiry Date: 06 July 2025

Certificate Number: ACT-1265



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

AND

ANSI/NCSL Z540-1-1994 (R2002)

Martin Calibration, Inc.

11965 12th Avenue South
Burnsville, MN 55337
Corey Garbers
952-882-1528

CALIBRATION AND DIMENSIONAL MEASUREMENT

Valid to: **July 6, 2025**

Certificate Number: **ACT-1265**

Satellite locations in:

[Mundelein, IL](#)

[Eau Claire, WI](#)



ANSI National Accreditation Board

Services performed at Main Site laboratory

Martin Calibration, Inc.

11965 12th Avenue South
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CALIBRATION

Acoustics and Vibration

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Sound Level – Fixed Points	(94, 104, 114) dB	0.2 dB	Bruel & Kjaer Sound Pressure Calibrator
Sound Level - Linearity	(50 to 143) dB	0.13 dB	
Sound Level - Frequency	(0.031 to 16) kHz	1 % of reading	
Sound Level - Distortion	(25 to 123) dB (0.031 to 16) kHz	0.14 dB	
Accelerometers	(5 to 9) Hz	2.6 % of reading	PCB Shaker Table with PCB Reference Accelerometer
	(10 to 99) Hz	1.6 % of reading	
	100 Hz	0.75 % of reading	
	(101 to 920) Hz	1.3 % of reading	
	921 Hz to 5 kHz	2.2 % of reading	
	(5 to 8) kHz	3.8 % of reading	
	(8 to 10) kHz	4.8 % of reading	
	(10 to 15) kHz	8.6 % of reading	

Chemical Quantities

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Conductivity Meters ¹	(0.86 to 10) μ S/cm	0.42 μ S/cm	Conductivity Standards
	(10 to 100) μ S/cm	0.89 μ S/cm	
	(100 to 1 500) μ S/cm	0.42 % of reading	
	12 800 μ S/cm	0.42 % of reading	
Refractometers	0.00 Brix	0.000 6 Brix	Calibration Solutions
	10.00 Brix	0.018 Brix	
	40.00 Brix	0.019 Brix	
	70.00 Brix	0.03 Brix	



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Chemical Quantities

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
pH Meters ¹	4 pH 7 pH 10 pH	0.016 pH 0.016 pH 0.016 pH	Buffer Solutions

Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Source ¹ Fixed Point	10V	0.5 μ V/V	732B Voltage Standards with Fluke Maps
DC Voltage – Source ¹	0V Up to 1 mV (1 to 10) mV (10 to 100) mV (100 mV to 1) V (1 to 10) V (10 to 100) V (100 to 1 100) V	20 nV 100 nV 22 μ V/V + 25 nV 5.3 μ V/V 0.5 μ V/V 0.31 μ V/V 0.35 μ V/V 1 μ V/V	MI Potentiometer/ Divider & Fluke 5720A Multi Product Calibrator
DC Voltage – Measure ¹	0V Up to 1 mV (1 to 10) mV (10 to 100) mV (100 mV to 1) V (1 to 10) V (10 to 100) V (100 to 1 100) V	20 nV 100 nV 22 μ V/V + 25 nV 5.3 μ V/V 0.5 μ V/V 0.31 μ V/V 0.35 μ V/V 1 μ V/V	Nano Voltmeter Fluke 732B Voltage Standard with MI Potentiometer/ Divider
DC High Voltage – Measure ¹	(1.1 to 10) kV (10 to 30) kV (30 to 50) kV (50 to 70) kV (70 to 100) kV	0.05 % of reading 0.055 % of reading 0.079 % of reading 0.12 % of reading 0.83 % of reading	Hipotronics KVM100-A High Voltage Meter
DC Current – Source & Measure ¹	0 A (0 to 200) pA (0.2 to 20) nA (20 to 100) nA	76 fA 1.9 % of reading + 10 fA 0.29 % of reading + 1 pA 8 μ A/A + 1.3 pA	Electrometer



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Source & Measure ¹	(0.1 to 1) μ A (1 to 10) μ A (10 to 100) μ A (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A	30 μ A/A 6.8 μ A/A 6.2 μ A/A 4.1 μ A/A 4.2 μ A/A 3.9 μ A/A 17 μ A/A	Standard resistors and DMM and Multifunction Calibrator
DC Current – Source & Measure ¹	(1 to 20) A (20 to 120) A	26 μ A/A 80 μ A/A + 4 mA	Fluke 52120A Amplifier with shunts
DC Current – Source ¹	(100 to 150) A (150 to 1 025) A	5 mA/A + 20 mA 5.1 mA/A + 0.9 A	Fluke 5520A Multi Product Calibrator with 50-turn Coil
DC Power – Source	10.9 μ W to 10.9 mW 10.9 mW to 3.06 kW (3.06 to 20.9) kW	0.18 mW/W 0.17 mW/W 0.54 mW/W	Fluke 5520A Multi Product Calibrator
AC Power – Source (45 to 65) Hz	109 μ W to 1.09 mW (1.09 to 297) μ W 297 μ W to 2.97 mW 2.97 mW to 337 W 337 W to 2.24 kW (2.24 to 20.9) kW	1.1 mW/W 930 μ W/W 780 μ W/W 620 μ W/W 700 μ W/W 780 μ W/W	Fluke 5520A Multi Product Calibrator
AC Voltage – Source & Measure ¹	(0 to 2.2) mV (10 to 20) Hz (20 to 40) Hz (0.04 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (0.5 to 1) MHz	1.1 mV/V + 1.3 μ V 490 μ V/V + 1.3 μ V 280 μ V/V + 1.3 μ V 540 μ V/V + 2 μ V 800 μ V/V + 2.5 μ V 1.5 mV/V + 4 μ V 1.6 mV/V + 8 μ V 2.3 mV/V + 8 μ V	Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator
AC Voltage – Source & Measure ¹	(2.2 to 7) mV (10 to 20) Hz (20 to 40) Hz (0.04 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (0.5 to 1) MHz	570 μ V/V + 1.3 μ V 250 μ V/V + 1.3 μ V 140 μ V/V + 1.3 μ V 270 μ V/V + 2 μ V 400 μ V/V + 2.5 μ V 800 μ V/V + 4 μ V 870 μ V/V + 8 μ V 1.5 mV/V + 8 μ V	Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source & Measure ¹	(7 to 22) mV		Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator
	(10 to 20) Hz	190 $\mu\text{V/V} + 1.3 \mu\text{V}$	
	(20 to 40) Hz	130 $\mu\text{V/V} + 1.3 \mu\text{V}$	
	(0.04 to 20) kHz	73 $\mu\text{V/V} + 1.3 \mu\text{V}$	
	(20 to 50) kHz	140 $\mu\text{V/V} + 2 \mu\text{V}$	
	(50 to 100) kHz	210 $\mu\text{V/V} + 2.5 \mu\text{V}$	
	(100 to 300) kHz	540 $\mu\text{V/V} + 4 \mu\text{V}$	
	(300 to 500) kHz	590 $\mu\text{V/V} + 8 \mu\text{V}$	
	(0.5 to 1) MHz	1.1 mV/V + 8 μV	
	(22 to 70) mV		
	(10 to 20) Hz	160 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(20 to 40) Hz	80 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(0.04 to 20) kHz	43 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(20 to 50) kHz	87 $\mu\text{V/V} + 2 \mu\text{V}$	
	(50 to 100) kHz	170 $\mu\text{V/V} + 2.5 \mu\text{V}$	
	(100 to 300) kHz	340 $\mu\text{V/V} + 4 \mu\text{V}$	
	(300 to 500) kHz	450 $\mu\text{V/V} + 8 \mu\text{V}$	
	(0.5 to 1) MHz	730 $\mu\text{V/V} + 8 \mu\text{V}$	
	(70 to 220) mV		
	(10 to 20) Hz	140 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(20 to 40) Hz	57 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(0.04 to 20) kHz	25 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(20 to 50) kHz	46 $\mu\text{V/V} + 2 \mu\text{V}$	
	(50 to 100) kHz	110 $\mu\text{V/V} + 2.5 \mu\text{V}$	
	(100 to 300) kHz	170 $\mu\text{V/V} + 4 \mu\text{V}$	
	(300 to 500) kHz	250 $\mu\text{V/V} + 8 \mu\text{V}$	
	(0.5 to 1) MHz	670 $\mu\text{V/V} + 8 \mu\text{V}$	
	(220 to 700) mV		
	(10 to 20) Hz	140 $\mu\text{V/V} + 1.5 \mu\text{V}$	
	(20 to 40) Hz	51 $\mu\text{V/V} + 1.5 \mu\text{V}$	
(0.04 to 20) kHz	22 $\mu\text{V/V} + 1.5 \mu\text{V}$		
(20 to 50) kHz	34 $\mu\text{V/V} + 2 \mu\text{V}$		
(50 to 100) kHz	53 $\mu\text{V/V} + 2.5 \mu\text{V}$		
(100 to 300) kHz	120 $\mu\text{V/V} + 4 \mu\text{V}$		
(300 to 500) kHz	200 $\mu\text{V/V} + 8 \mu\text{V}$		
(0.5 to 1) MHz	640 $\mu\text{V/V} + 8 \mu\text{V}$		



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source & Measure ¹	(0.7 to 2.2) V		Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator
	(10 to 20) Hz	130 μ V/V	
	(20 to 40) Hz	44 μ V/V	
	(0.04 to 20) kHz	16 μ V/V	
	(20 to 50) kHz	31 μ V/V	
	(50 to 100) kHz	47 μ V/V	
	(100 to 300) kHz	110 μ V/V	
	(300 to 500) kHz	170 μ V/V	
	(0.5 to 1) MHz	600 μ V/V	
	(2.2 to 7) V		
	(10 to 20) Hz	130 μ V/V	
	(20 to 40) Hz	45 μ V/V	
	(0.04 to 20) kHz	16 μ V/V	
	(20 to 50) kHz	32 μ V/V	
	(50 to 100) kHz	54 μ V/V	
	(100 to 300) kHz	130 μ V/V	
	(300 to 500) kHz	270 μ V/V	
	(0.5 to 1) MHz	800 μ V/V	
	(7 to 22) V		
	(10 to 20) Hz	130 μ V/V	
	(20 to 40) Hz	45 μ V/V	
	(0.04 to 20) kHz	18 μ V/V	
	(20 to 50) kHz	32 μ V/V	
	(50 to 100) kHz	54 μ V/V	
	(100 to 300) kHz	130 μ V/V	
	(300 to 500) kHz	270 μ V/V	
	(0.5 to 1) MHz	800 μ V/V	
	(22 to 70) V		
(10 to 20) Hz	130 μ V/V		
(20 to 40) Hz	45 μ V/V		
(0.04 to 20) kHz	21 μ V/V		
(20 to 50) kHz	38 μ V/V		
(50 to 100) kHz	63 μ V/V		
(100 to 300) kHz	130 μ V/V		
(300 to 500) kHz	270 μ V/V		
(0.5 to 1) MHz	800 μ V/V		



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source & Measure	(70 to 220) V		Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator
	(10 to 20) Hz	130 μ V/V	
	(20 to 40) Hz	45 μ V/V	
	(0.04 to 20) kHz	21 μ V/V	
	(20 to 50) kHz	46 μ V/V	
	(50 to 100) kHz	65 μ V/V	
	(100 to 300) kHz	140 μ V/V	
	(300 to 500) kHz	330 μ V/V	
	(220 to 700) V		
	(10 to 20) Hz	130 μ V/V	
	(20 to 40) Hz	66 μ V/V	
	(0.04 to 20) kHz	27 μ V/V	
	(20 to 50) kHz	87 μ V/V	
	(50 to 100) kHz	330 μ V/V	
AC Voltage – Source & Measure Flatness relative to 1 kHz	(0 to 2.2) mV		Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator (Wideband)
	(10 to 30) Hz	0.1 % of reading + 1.3 μ V	
	(30 to 120) Hz	0.05 % of reading + 1.3 μ V	
	(0.12 to 1.2) kHz	0.05 % of reading + 1.3 μ V	
	(1.2 to 120) kHz	0.05 % of reading + 2 μ V	
	(120 to 500) kHz	0.07 % of reading + 1 μ V	
	(0.5 to 1.2) MHz	0.07 % of reading + 1 μ V	
	(1.2 to 2) MHz	0.07 % of reading + 1 μ V	
	(2 to 10) MHz	0.17 % of reading + 1 μ V	
	(10 to 20) MHz	0.32 % of reading + 1 μ V	
	(20 to 30) MHz	0.7 % of reading + 2 μ V	
	(2.2 to 7) mV		
	(10 to 30) Hz	0.1 % of reading	
	(30 to 120) Hz	0.05 % of reading	
	(0.12 to 1.2) kHz	0.05 % of reading	
	(1.2 to 120) kHz	0.05 % of reading	
	(120 to 500) kHz	0.07 % of reading + 1 μ V	
	(0.5 to 1.2) MHz	0.07 % of reading + 1 μ V	
	(1.2 to 2) MHz	0.07 % of reading + 1 μ V	
	(2 to 10) MHz	0.1 % of reading + 1 μ V	
	(10 to 20) MHz	0.17 % of reading + 1 μ V	
	(20 to 30) MHz	0.37 % of reading + 1 μ V	



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source & Measure Flatness relative to 1 kHz	(7 to 22) mV		Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator (Wideband)
	(10 to 30) Hz	0.1 % of reading	
	(30 to 120) Hz	0.05 % of reading	
	(0.12 to 1.2) kHz	0.05 % of reading	
	(1.2 to 120) kHz	0.05 % of reading	
	(120 to 500) kHz	0.07 % of reading	
	(0.5 to 1.2) MHz	0.07 % of reading	
	(1.2 to 2) MHz	0.07 % of reading	
	(2 to 10) MHz	0.1 % of reading	
	(10 to 20) MHz	0.17 % of reading	
	(20 to 30) MHz	0.37 % of reading	
	(22 to 70) mV		
	(10 to 30) Hz	0.1 % of reading	
	(30 to 120) Hz	0.05 % of reading %	
	(0.12 to 1.2) kHz	0.05 % of reading	
	(1.2 to 120) kHz	0.05 % of reading	
	(120 to 500) kHz	0.05 % of reading	
	(0.5 to 1.2) MHz	0.05 % of reading	
	(1.2 to 2) MHz	0.05 % of reading	
	(2 to 10) MHz	0.1 % of reading	
	(10 to 20) MHz	0.15 % of reading	
	(20 to 30) MHz	0.35 % of reading	
	(70 to 220) mV		
	(10 to 30) Hz	0.1 % of reading	
	(30 to 120) Hz	0.04 % of reading	
	(0.12 to 1.2) kHz	0.04 % of reading	
	(1.2 to 120) kHz	0.04 % of reading	
(120 to 500) kHz	0.04 % of reading		
(0.5 to 1.2) MHz	0.05 % of reading		
(1.2 to 2) MHz	0.05 % of reading		
(2 to 10) MHz	0.1 % of reading		
(10 to 20) MHz	0.15 % of reading		
(20 to 30) MHz	0.35 % of reading		



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source & Measure Flatness relative to 1 kHz	(220 to 700) mV (10 to 30) Hz (30 to 120) Hz (0.12 to 1.2) kHz (1.2 to 120) kHz (120 to 500) kHz (0.5 to 1.2) MHz (1.2 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz (0.7 to 2.2) V (10 to 30) Hz (30 to 120) Hz (0.12 to 1.2) kHz (1.2 to 120) kHz (120 to 500) kHz (0.5 to 1.2) MHz (1.2 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz (2.2 to 7) V (10 to 30) Hz (30 to 120) Hz (0.12 to 1.2) kHz (1.2 to 120) kHz (120 to 500) kHz (0.5 to 1.2) MHz (1.2 to 2) MHz (2 to 10) MHz (10 to 20) MHz (20 to 30) MHz	0.1 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.05 % of reading 0.05 % of reading 0.1 % of reading 0.15 % of reading 0.35 % of reading 0.1 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.05 % of reading 0.05 % of reading 0.1 % of reading 0.15 % of reading 0.35 % of reading 0.1 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.03 % of reading 0.05 % of reading 0.05 % of reading 0.1 % of reading 0.15 % of reading 0.35 % of reading	Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator (Wideband)
AC Current – Source ¹	9 μA to 1 mA DC to 10 kHz 1 mA to 1 A DC to 10 kHz (1 to 20) A DC to 10 kHz	75 μA/A 28 μA/A 52 μA/A	Fluke 5720A Multi Product Calibrator w/ A40B Shunts



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	(20 to 120) A DC to 1 kHz (1 to 6) kHz	3 mA/A 12 mA/A	Fluke 5720A Multi Product Calibrator w/ A40B Shunts
AC Current – Measure ¹	9 μ A to 1 mA (DC to 30) kHz (30 to 100) kHz 1mA to 1A (DC to 100) kHz (1 to 20) A (DC to 10) kHz (10 to 30) kHz (30 to 100) kHz	90 μ A/A 0.18 mA/A 35 μ A/A 61 μ A/A 83 μ A/A 0.13 mA/A	Fluke A40B Shunts
AC Current – Measure ¹	9 μ A to 200 μ A (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz 200 μ A to 2 mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz	0.62 mA/A 0.54 mA/A 0.94 mA/A 8.4 mA/A 0.6 mA/A 0.54 mA/A 0.94 mA/A 4.2 mA/A	Fluke 8508A Multimeter
AC Current – Measure ¹	(2 to 20) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz (20 to 200) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz 200 mA to 2 A 10 Hz to 2 kHz (2 to 10) kHz (10 to 30) kHz (2 to 20) A 10 Hz to 2 kHz (2 to 10) kHz	0.6 mA/A 0.54 mA/A 0.94 mA/A 4.2 mA/A 0.57 mA/A 0.49 mA/A 0.83 mA/A 0.83 mA/A 0.93 mA/A 3.2 mA/A 1 mA/A 2.7 mA/A	Fluke 8508A Multimeter



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source ¹	0.001 Ω	3.5 μΩ/Ω	Standard resistors
	0.01Ω	4.3 μΩ/Ω	
	0.1 Ω	1.5 μΩ/Ω	
	1Ω	0.67 μΩ/Ω	
	10Ω	0.56 μΩ/Ω	
	100 Ω	0.68 μΩ/Ω	
	1 kΩ	0.51 μΩ/Ω	
	10 kΩ	0.8 μΩ/Ω	
	100 kΩ	0.57 μΩ/Ω	
	1 MΩ	1.3 μΩ/Ω	
	10 MΩ	14 μΩ/Ω	
	100 MΩ	130 μΩ/Ω	
	1 GΩ	26 μΩ/Ω	
	(1 to 10) GΩ	0.16 % of reading	
	(10 to 100) GΩ	0.54 % of reading	
(100 to 900) GΩ	0.56 % of reading		
1 TΩ	1.6 % of reading		
10 TΩ	1.7 % of reading		
Resistance – Measure ¹	(10 to 100) μΩ	0.15 % of reading	Standard resistors with bridge and DMM
	(0.1 to 1) mΩ	15 μΩ/Ω	
	(1 to 10) mΩ	5.1 μΩ/Ω	
	(10 to 100) mΩ	1.8 μΩ/Ω	
	(0.1 to 1) Ω	0.67 μΩ/Ω	
	(1 to 10) Ω	0.56 μΩ/Ω	
Resistance – Measure ¹	(10 to 100) Ω	0.68 μΩ/Ω	Standard resistors with bridge and DMM
	(0.1 to 1) kΩ	0.51 μΩ/Ω	
	(1 to 10) kΩ	0.8 μΩ/Ω	
	(10 to 100) kΩ	0.57 μΩ/Ω	
	(0.1 to 1) MΩ	1.3 μΩ/Ω	
Resistance – Measure ¹	(1 to 10) MΩ	14 μΩ/Ω	Decade resistors with bridge and DMM
	(10 to 200) MΩ	72μΩ/Ω + 1kΩ	
	(0.2 to 2) GΩ	0.18 mΩ/Ω + 100 kΩ	
Resistance – Measure ¹	(2 to 20) GΩ	0.67 mΩ/Ω + 10 MΩ	Decade resistors with bridge and DMM
	(2 to 20) MΩ	15 μΩ/Ω + 10 Ω	
	(20 to 200) MΩ	60 μΩ/Ω + 1 kΩ	
Resistance – Measure ¹ High Voltage Mode up to 200 V	200 MΩ to 2 GΩ	0.15 mΩ/Ω + 100 kΩ	Decade resistors with bridge and DMM
	(2 to 20) GΩ	0.53 mΩ/Ω + 10 MΩ	



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Resistance (Impedance)	(1, 500) kHz, 1 MHz 25 Ω 375 Ω (1, 250, 500) kHz, 1 MHz 6 kΩ (1, 25, 50) kHz 100 kΩ	100 μΩ/Ω	AC Resistor Set
Capacitance – Measure ¹	1 pF @ 1 kHz 10 pF @ 1 kHz 100 pF @ 1kHz 1 nF 1kHz 1 μF @ 1 kHz	1.9 mF/F 1.1 mF/F 1.2 mF/F 1.2 mF/F 1.2 mF/F	QuadTech 1730 LCR Meter
Capacitance – Source ¹ (fixed values) @ 100 Hz @ 1 kHz	1 pF 1 nF 10 nF 100 nF 1 μF	1.8 mF/F 0.23 mF/F 0.25 mF/F 0.21 mF/F 0.25 mF/F	Standard Capacitors
Capacitance – Source ¹ 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz (10 to 600) Hz 10 Hz to 300 Hz 10 Hz to 150 Hz 10 Hz to 120 Hz	0.19 nF to 1.1 nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 110) nF (110 to 330) nF 330 nF to 1.1 μF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF	15 mF/F 8.4 mF/F 3.6 mF/F 3.6 mF/F 3.7 mF/F 3.6 mF/F 3.6 mF/F 3.6 mF/F 5.1 mF/F	Fluke 5520A Multi Product Calibrator
Capacitance – Source ¹ 10 Hz to 80 Hz (0 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	(33 to 110) μF (110 to 330) μF 330 μF to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	5.6 mF/F 5.6 mF/F 8.7 mF/F 5.5 mF/F 5.5 mF/F 8.5 mF/F 12 mF/F	Fluke 5520A Multi Product Calibrator
Inductance – Measure ¹	100 μH @ 1 kHz 1 mH @ 1 kHz 10 mH @ 1 kHz 100 mH @ 1 kHz 1 H @ 1 kHz	1.3 mH/H	QuadTech 1730 LCR Meter



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Inductance – Source ¹	500 μ H @ 100 Hz 500 μ H @ 1 kHz 2 mH @ 100 Hz 2 mH @ 1 kHz 20 mH @ 100 Hz 20 mH @ 1 kHz 1 H @ 100 Hz 1 H @ 1 kHz 10 H @ 100 Hz 10 H @ 1 kHz	1.2 mH/H 1 mH/H 1.1 mH/H 1 mH/H 1.1 mH/H 1 mH/H 1 mH/H 1 mH/H 1 mH/H 1 mH/H	Standard Inductors
Oscilloscopes ¹ Square Wave Signal 50 Ω at 1 kHz Square Wave Signal 1 M Ω at 1 kHz DC Voltage, 50 Ω DC Voltage, 1 M Ω Leveled Sine Wave Amplitude Leveled Sine Wave Flatness (relative to 50 kHz)	40 μ V to 5 V 40 μ V to 5 V 1 mV to 5 V 1 mV to 200 V 5 mV to 5 V 4.4 mVpp to 5.6 Vpp 0.1 Hz to 300 MHz (300 to 550) MHz	1 mV/V 1 mV/V 0.26 mV/V 0.25 mV/V 15 mV/V 43 mV/V 43 mV/V	Fluke 9500B/3200/9530 Oscilloscope Calibrator
Oscilloscopes ¹ Leveled Sine Wave Flatness (relative to 50 kHz) Time Marker 50 Ω Source and Period Rise/Fall Time - Source Pulse Width - Source	4.4 mVpp to 3.3 Vpp 550 MHz to 1.1 GHz (1.1 to 3.2) GHz 9 ns to 55 s 150 ps (1 to 100) ns	52 mV/V 52 mV/V 0.25 μ s/s 27 ps 52 ms/s	Fluke 9500B/3200/9530 Oscilloscope Calibrator



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Electrical – DC/Low Frequency

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Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type B		Ectron 1140A Thermocouple Simulator
	(250 to 350) °C	1.1 °C	
	(350 to 445) °C	0.85 °C	
	(445 to 580) °C	0.67 °C	
	(580 to 750) °C	0.52 °C	
	(750 to 1 000) °C	0.43 °C	
	(1 000 to 1 820) °C	0.33 °C	
	Type C		
	(0 to 250) °C	0.23 °C	
	(250 to 1 000) °C	0.18 °C	
	(1 000 to 1 500) °C	0.21 °C	
	(1 500 to 1 800) °C	0.24 °C	
	(1 800 to 2 000) °C	0.27 °C	
	(2 000 to 2 250) °C	0.33 °C	
	(2 250 to 2 315) °C	0.37 °C	
	Type E		
	(-270 to -245) °C	1.38 °C	
	(-245 to -195) °C	0.21 °C	
	(-195 to -155) °C	0.12 °C	
	(-155 to -90) °C	0.09 °C	
	(-90 to 15) °C	0.08 °C	
	(15 to 890) °C	0.07 °C	
	(890 to 1 000) °C	0.08 °C	
	Type J		
(-210 to -180) °C	0.14 °C		
(-180 to -120) °C	0.12 °C		
(-120 to -50) °C	0.09 °C		
(-50 to 990) °C	0.08 °C		
(990 to 1 200) °C	0.08 °C		
Type K			
(-270 to -255) °C	2.5 °C		
(-255 to -195) °C	0.81 °C		
(-195 to -115) °C	0.14 °C		
(-115 to -55) °C	0.1 °C		
(-55 to 1 000) °C	0.08 °C		
(1 000 to 1 372) °C	0.09 °C		



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Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type N (-270 to -260) °C (-260 to -200) °C (-200 to -140) °C (-140 to -70) °C (-70 to 25) °C (25 to 160) °C (160 to 1 300) °C Type R (-50 to -30) °C (-30 to 45) °C (45 to 160) °C (160 to 380) °C (380 to 775) °C (775 to 1 768) °C Type S (-50 to -30) °C (-30 to -45) °C (-45 to -105) °C (-105 to 310) °C (310 to 615) °C (615 to 1 768) °C Type T (-270 to -255) °C (-255 to -240) °C (-240 to -210) °C (-210 to -150) °C (-150 to -40) °C (-40 to 100) °C (100 to 400) °C	5.8 °C 1.2 °C 0.27 °C 0.17 °C 0.14 °C 0.12 °C 0.1 °C 0.75 °C 0.63 °C 0.46 °C 0.35 °C 0.3 °C 0.25 °C 0.71 °C 0.64 °C 0.46 °C 0.38 °C 0.33 °C 0.3 °C 2.1 °C 0.56 °C 0.35 °C 0.21 °C 0.14 °C 0.09 °C 0.08 °C	Ectron 1140A Thermocouple Simulator
Electrical Simulation of RTD Indicators ¹	PT 395 100 Ω (-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.06 °C 0.08 °C 0.11 °C 0.12 °C 0.14 °C 0.27 °C	Fluke 5520A Multi Product Calibrator



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Electrical – DC/Low Frequency

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Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicators ¹	PT 3926 100 Ω		Fluke 5520A Multi Product Calibrator
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	PT 3916 100 Ω		
	(-200 to -190) °C	0.29 °C	
	(-190 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.06 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 260) °C	0.08 °C	
	(260 to 300) °C	0.09 °C	
	(300 to 400) °C	0.11 °C	
	(400 to 600) °C	0.12 °C	
	(600 to 630) °C	0.27 °C	
	PT 385 200 Ω		
	(-200 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.14 °C	
	(300 to 400) °C	0.15 °C	
	(400 to 600) °C	0.16 °C	
	(600 to 630) °C	0.19 °C	
	PT 385 500 Ω		
	(-200 to -80) °C	0.05 °C	
	(-80 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
	(260 to 400) °C	0.09 °C	
(400 to 600) °C	0.01 °C		
(600 to 630) °C	0.13 °C		
PT 395 100 Ω			
(-200 to 0) °C	0.06 °C		
(0 to 100) °C	0.08 °C		
(100 to 300) °C	0.11 °C		
(300 to 400) °C	0.12 °C		
(400 to 630) °C	0.14 °C		
(630 to 800) °C	0.27 °C		

Electrical – DC/Low Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicators ¹	PT 3926 100 Ω		Fluke 5520A Multi Product Calibrator
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	PT 3916 100 Ω		
	(-200 to -190) °C	0.29 °C	
	(-190 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.06 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 260) °C	0.08 °C	
	(260 to 300) °C	0.09 °C	
	(300 to 400) °C	0.11 °C	
	(400 to 600) °C	0.12 °C	
	(600 to 630) °C	0.27 °C	
	PT 385 200 Ω		
	(-200 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.14 °C	
	(300 to 400) °C	0.15 °C	
	(400 to 600) °C	0.16 °C	
	(600 to 630) °C	0.19 °C	
	PT 385 500 Ω		
	(-200 to -80) °C	0.05 °C	
	(-80 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
	(260 to 400) °C	0.09 °C	
(400 to 600) °C	0.01 °C		
(600 to 630) °C	0.13 °C		
PT 385 1 000 Ω			
(-200 to 0) °C	0.04 °C		
(0 to 100) °C	0.05 °C		
(100 to 260) °C	0.06 °C		
(260 to 300) °C	0.07 °C		
(300 to 600) °C	0.08 °C		
(600 to 630) °C	0.27 °C		
PtNi 120 Ω			
(-80 to 100) °C	0.09 °C		
(100 to 260) °C	0.16 °C		
Cu 427 10 Ω			
(-100 to 260) °C	0.35 °C		

Electrical – RF/Microwave

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RF Power - Measure Absolute Level ¹	(-36 to 20) dBm 9 kHz to 6 GHz	0.16 dB	Agilent E9304A/N1912A Agilent N5531S Measuring Receiver with N5532A Sensor Module
	(20 to 30) dBm (6 to 18) GHz	0.44 dB	
	(18 to 26.5) GHz	0.5 dB	
RF Power - Measure Absolute Level ¹	(-20 to 20) dBm 100 kHz to 30 MHz	0.2 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Module
	30 MHz to 2 GHz (1 to 18) GHz	0.21 dB	
	(18 to 26.5) GHz	0.31 dB	
		0.4 dB	
RF Power - Measure Absolute Level ¹	(-30 to 20) dBm 100 kHz to 30 MHz	3.1 % of reading	Agilent N5531S Measuring Receiver with 8482A Sensor
Relative Power – Measure ¹ 100 kHz to 26.5 GHz	(-10 to 0) dB	0.02 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Module
	(-20 to -10) dB	0.03 dB	
	(-30 to -20) dB	0.03 dB	
	(-40 to -30) dB	0.05 dB	
	(-50 to -40) dB	0.06 dB	
	(-60 to -50) dB	0.06 dB	
	(-70 to -60) dB	0.07 dB	
(-80 to -70) dB	0.07 dB		
Relative Power – Measure ¹ 100 kHz to 26.5 GHz	(-90 to -80) dB	0.08 dB	Agilent N5531S Measuring Receiver with N5532A Sensor Module
	(-100 to -90) dB	0.08 dB	
	(-110 to -100) dB	0.09 dB	
	(-120 to -110) dB	0.1 dB	
	(-130 to -120) dB	0.1 dB	
(-140 to -130) dB	0.1 dB		
RF Power – Source ¹	(-90 to -75) dBm 250 kHz to 2 GHz	0.73 dB	Agilent N5183A Signal Generator
	(2 to 20) GHz	1 dB	
	(20 to 32) GHz	1.2 dB	
	(-75 to -10) dBm 250 kHz to 2 GHz	0.72 dB	
	(2 to 20) GHz	1 dB	
	(20 to 32) GHz	1.2 dB	
	(-20 to -10) dBm 250 kHz to 2 GHz	1.4 dB	
	(2 to 20) GHz	1.3 dB	
	(20 to 32) GHz	1.3 dB	



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Electrical – RF/Microwave

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RF Power – Source ¹	(-10 to 10) dBm 250 kHz to 2 GHz (2 to 20) GHz (20 to 32) GHz > 10 dBm 250 kHz to 2 GHz (2 to 20) GHz (20 to 32) GHz	0.61 dB 0.91 dB 0.93 dB 0.63 dB 0.92 dB 1 dB	Agilent N5183A Signal Generator
Phase Modulation - Source ¹ 100 kHz to 32 GHz	Rate: DC to 1 MHz DC to 4 MHz	0.59 % of reading + 0.01 rad	Agilent N5183A Signal Generator
LO Phase Noise @ 1GHz	(-50 to 20) dB Frequency offset: (0.10 to 1 000) Hz (1 to 9 900) kHz	0.48 dB 0.64 dB	Keysight E4440A Spectrum Analyzer
Amplitude Modulation ¹ - Source 100 kHz to 32 GHz	Rate: DC to 10 kHz Depths: (1 to 90) %	4.1 % of reading	Agilent N5183A Signal Generator
Amplitude Modulation - Measure ¹ 100 kHz to 10 MHz 10 MHz to 3 GHz 10 MHz to 3 GHz (3 to 26.5) GHz (3 to 26.5) GHz	Rate: 20 Hz to 10 kHz Depths: (5 to 99) % Rate: 50 Hz to 100 kHz Depths: (20 to 99) % Rate: 50 Hz to 100 kHz Depths: (5 to 20) % Rate: 50 Hz to 100 kHz Depths: (20 to 99) % Rate: 50 Hz to 100 kHz Depths: (5 to 20) %	0.83 % of reading 0.59 % of reading 2.6 % of reading 1.6 % of reading 4.7 % of reading	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
Pulse Generation – Source ¹ Repetition Frequency: 0.10 Hz to 10.0 MHz	30 ns to 42 s	10 ns	Agilent N5183A Signal Generator

Electrical – RF/Microwave

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment	
Phase Modulation-Measure ¹ 100 kHz to 6.6 GHz 100 kHz to 6.6 GHz (6.6 to 13.2) GHz (6.6 to 13.2) GHz (13.2 to 26.5) GHz (13.2 to 26.5) GHz	Rate: 200 Hz 20 kHz Dev.: > 0.7 rad Rate:200 Hz, 20 kHz Dev.>0.3 rad Rate: 200 Hz 20 kHz Dev.: > 2.0 rad Rate: 200 Hz 20 kHz Dev.: > 0.6 rad Rate: 200 Hz 20 kHz Dev.: > 2.0 rad Rate: 200 Hz 20 kHz Dev.: > 0.6 rad	1.1 % of reading 3.1 % of reading 1.1 % of reading 3.1 % of reading 1.1 % of reading 3.1 % of reading	Agilent N5531S Measuring Receiver with N5532A Sensor Modules	
Frequency Modulation ¹ - Source 100 kHz to 32 GHz	1 dB Rate: DC to 3 MHz 3 dB Rate: DC to 7 MHz	2 % of setting + 20 Hz		Agilent N5183A Signal Generator
Freq Modulation-Measure ¹ Freq. Dev. Mod Rate Ratio >0.2 250 kHz to 10 MHz 250 kHz to 10 MHz 10 MHz to 6.6 GHz	Rate: 20 Hz to 10 kHz Dev.: 200 Hz to 40 kHz peak Freq. Dev. Mod Rate Ratio >0.2 Rate: 20 Hz to 10 kHz Dev.: 200 Hz to 40 kHz peak Freq. Dev. Mod Rate Ratio >1.2 Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak Freq. Dev. Mod Rate Ratio >0.2	1.6 % of reading 1.1 % of reading 1.6 % of reading		Agilent N5531S Measuring Receiver with N5532A Sensor Modules

Electrical – RF/Microwave

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Freq Modulation-Measure ¹ Freq. Dev. Mod Rate Ratio >0.2 10 MHz to 6.6 GHz	Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak Freq. Dev. Mod Rate Ratio >0.45	1.1 % of reading	Agilent N5531S Measuring Receiver with N5532A Sensor Modules
(6.6 to 13.2) GHz	Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak Freq. Dev. Mod Rate Ratio >0.2	2.6 % of reading	
(6.6 to 13.2) GHz	Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak Freq. Dev. Mod Rate Ratio >8	1.1 % of reading	
(13.2 to 26.5) GHz	Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak Freq. Dev. Mod Rate Ratio >0.2	3.9 % of reading	
(13.2 to 26.5) GHz	Rate: 50 Hz to 200kHz Dev.: 250 Hz to 400 kHz peak	1.1 % of reading	

Length – Dimensional Metrology

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Angle	(0.25 to 365)°	2.4 arc sec	Gage Blocks, Gage Amplifier, Sine Bar
Angle Plates – Squareness ²	Up to 18 in	0.32 m° (5.6 µin/ in)	Gage Amplifier with probe, Master Square(s)



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Length – Dimensional Metrology

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gage Blocks ²	(0.01 to 1) in (2 to 3) in 4 in	(1.1 + 0.4L) μin (1.2 + 0.7L) μin 4.6 μin	Gage Blocks Gage Block Comparator
	(5 to 12) in (12 to 20) in	(5 + 2L) μin (2 + 2.8L) μin	Horizontal Measuring Machine
	100 mm (125 to 500) mm	0.17 μm (0.06 + 0.000 6L) μm	Comparison to Primary Master Gage Blocks
Indicators ^{1,2}	(0.000 1 to 6) in	(5+8L) μin	Horizontal Measuring Machine
Calipers ^{1,2}	Up to 60 in	(5+8L) μin	Gage Blocks
Micrometers OD ^{1,2}	Up to 12 in	(5+8L) μin	Gage Blocks, Optical Parallels
Height Measuring Devices ^{1,2}	Up to 36 in (36 to 48) in	(43 + 1.7L) μin (7 + 3L) μin	Gage Blocks
Grind Gages	Up to 100 mm	0.35 mm	Digital Indicator
Coating Thickness Gages ^{1,2}	Up to 0.02 in	58 μin + 0.6R	Coating Thickness Standards
Coating Thickness Gage Standards	Up to 0.10 in	21 μin	Horizontal Measuring Machine
External Diameter ^{1,2}	(0.000 1 to 1) in (1 to 12) in	(3 + 1L) μin (3 + 3L) μin	Horizontal Measuring Machine
Internal Diameter ^{1,2}	(0.04 to 13) in	(3 + 3L) μin	Horizontal Measuring Machine
Thread Plugs ^{1,2} Pitch Diameter	Up to 8 in Pitch (0.2 to 5) mm	(81 + 2.3L) μin	Horizontal Measuring Machine
Major Diameter	Pitch 90 – 4 TPI Up to 4 in	(3.5 + 4.6L) μin	Thread Measuring Wires
Thread Rings (Adjustable) Pitch Diameter Tactile Fit (Set to Plug)	Up to 4 in	See footnote ⁵	Thread Setting Plug
Optical Comparators ^{1,2} Linear Accuracy	Up to 6 in 6 to 12 in	(43 + 11L) μin (30 + 7.5L) μin	Glass Scale
Magnification	(5 to 100) X	350 μin	Glass Scale (Sphere)

Length – Dimensional Metrology

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Surface Plates ^{1,2} Overall Flatness	Up to 54 inDL (54 to 238) inDL	(17 + 0.7DL) μin (1 + 1.4DL) μin	Laser System
Local Area Flatness	Up to 238 inDL	34 μin	Repeat-O-Meter
Roundness/Cylindricity Artifacts	Up to 150 mm	0.02 μm	Rondcom41c
Surface Finish Artifacts	Up to 118 μin 118.1 to 500 μin	0.5 μin + 1 % of nominal 0.6 μin + 1.1 % of nominal	Profilometer, Master Patch
Profilometers ¹	Up to 500 μin	0.7 μin + 1.1 % of nominal	Master Patch
Optical Flats Parallelism Flatness	Up to 6 inD (0 to 80) μin	2.7 μin 3.5 μin	Gage Block Comparator, Master Flat
CMMs ^{1,2} Linearity	(0 to 144) in	(25 + 2.4L) μin	Laser Measuring System
Volumetric Repeatability	(6 to 24) in (0.5 to 2) in	66 μin 45 μin	Ball Bar CMM Sphere
VMMs ^{1,2}	Linearity	(32 + 4.1L) μin	Glass Scales
Graduated Scales ^{1,2} Glass, Steel, Tape	Up to 12 in (1 to 200) ft	(40 + 1L) μin (10+ 3L) μin	Laser Measuring System
Horizontal Measuring Systems ^{1,2}	Up to 8 in (8 to 60) in	(6 + 1.7L) μin (3 + 2.5L) μin	Gage Blocks
Bore Gages ² 2-point	(0.24 to 9) in	(4.3 + 3L) μin + 0.6R	Horizontal Measuring Machine
3-point		(85 + 7L) μin + 0.6R	Cylindrical Rings
Protractors	(0 to 90)°	0.16°	Sine Bar, Gage Blocks
Chamfer Gages ²	(0.179 to 2.749) in	280 μin + 0.6R	Chamfer Rings
Cylindrical Squares - Squareness	Up to 12 in	1.5 arc seconds	Gage Amplifier w/ probe, Master Square(s)
Cylindricity		0.02 μm	Roundness Machine
Feeler/Thickness Gages ²	Up to 0.2 in	(4.3 + 3L) μin	Horizontal Measuring System
Gage Amplifier w/ Probe(s)	Up to 0.1 in	10 μin	Gage Blocks

Length – Dimensional Metrology

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gage Balls/Spheres ² - Diameter	Up to 6 in	$(4.3 + 3D) \mu\text{in}$	Gage Blocks, Horizontal Measuring System
Roundness		$0.02 \mu\text{m}$	Roundness Machine
Indicator Calibrator ² - Linearity	Up to 6 in	$60 \mu\text{in} + 0.6R$	Horizontal Measuring System
Groove Micrometers ²	Up to 12 in	$(44 + 2.6L) \mu\text{in} + 0.6R$	Gage Blocks
Machinist Levels ² – Zero Check Linearity	Up to 24 in	$350 \mu\text{in}$ $(100 + 0.83L) \mu\text{in}$	Master Level Gage Blocks
Microscopes, Stereo Reticle Linearity	Up to 2 in	$870 \mu\text{in}$	Stage Micrometer
Microscopes – Toolmakers ² Scale Linearity	Up to 4 in	$(774 + 70L) \mu\text{in} + 0.6R$	Stage Micrometer
Length Standards ²	(1 to 60) in	$(3.4 + 3.5L) \mu\text{in}$	Horizontal Measuring System
Micrometers – Inside ²	Up to 8 in 8 to 60 in	$(6 + 1.7L) \mu\text{in}$ $(3 + 2.5L) \mu\text{in}$	Horizontal Measuring System
Pi Tapes ² – Length	Up to 12 in	$(40 + 1L) \mu\text{in}$ $(10 + 3L) \mu\text{in}$	Laser System
Thickness	(12 to 200) in	$240 \mu\text{in}$	Micrometer
Parallels ² – Steel	Up to 18 in	$(96 + 1.8L) \mu\text{in}$	Electronic Amplifier with Probe
Granite		$(49 + 0.7L) \mu\text{in}$	Surface Plate
Pitch Micrometer Standard ² Length	(1 to 65) in	$(3.4 + 3.5L) \mu\text{in}$	Horizontal Measuring System
Angle	60°	$0.004^\circ (70 \mu\text{in}/\text{in})$	Vision System
Radius Gages	(0.015 625 to 0.5) in	$300 \mu\text{in}$	Vision System
Sine Plates/Bars ² – Top Surface Flatness	Up to 0.1 in	$(41 + 2.2L) \mu\text{in}$	Electronic Amplifier with Probe
Overall Length	Up to 10 in	$(3.4 + 3.5L) \mu\text{in}$	Horizontal Measuring System

Length – Dimensional Metrology

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Squares ²	Up to 18 in	0.32 m° (5.6 μin/ in)	Electronic Amplifier with Probe, Master Square
Straightness and Straight Edges ²	Up to 60 in	(208 + 2.3L) μin	Electronic Amplifier with Probe, Surface Plate
Tapered Plugs ² - Pitch Diameter Major Diameter Step Height	(0.0625 to 6) in	(137 + 3.3L) μin (123 + 6.7L) μin 280 μin	Horizontal Measuring System, Sine Block Thread Wires Height Gage
Roundness Machine - Roundness (Spindle Performance)	Up to 0.016 in	15 μin	Master Sphere
Tapered Rings - Pitch Diameter Step Height	(0.0625 to 6) in	160 μin 5 μin	NPT Master Plug, Electronic Amplifier with Probe Height Gage
Thickness Gages ² - Dial Digital	Up to 1 in	410 μin + 0.6R 44 μin+ 0.6R	Gage Blocks
Thread Micrometers ² (Screw Thread, Pitch Point) Linearity Anvil Wear	Up to 12 in	(44 + 2.6L) μin + 0.6R 690 μin	Gage Blocks Thread Setting Plug
Granite V Blocks - Side Parallelism V Parallelism Squareness	Up to 12 in	(51 + 0.47L) μin	Electronic Amplifier with Probe, Surface Plate
Extensometers ¹	Up to 2 in	16 μin	Extensometer Calibrator
Extensometers ¹ Gage Length	(0 to 2) in	78 μin	Caliper



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Mass and Mass Related

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force ¹ Source and Measure	(0.035 to 16) ozf (1 to 10) lbf (10 to 50) lbf (50 to 500) lbf	0.017 % of reading 0.018 % of reading 0.018 % of reading 0.036 % of reading	Dead Weight
	(500 to 100 000) lbf	0.04 % of reading	Load Cells
	(30 000 to 400 000) lb	0.29 % of applied value	Load Cells, Class A (compression only)
Test Machine Crosshead Displacement ^{1,2}	Up to 1 in (1 to 36) in	0.000 3 in (150 + 146L) μin	Indicator Indicator/Gage Blocks
Cable Tensiometers	Up to 600 lb (600 to 2 000) lb	1.2 % of applied value 1.3 % of applied value	Dead Weight Load Cells
Viscometers ¹	Up to 25 cP (25 to 1 500) cP (1 500 to 75 000) cP	0.33 % of reading 0.52 % of reading 0.55 % of reading	Viscosity Standards
Pressure ¹	(10 to 17) psia	0.000 4 psi	Pressure Calibrator
Pressure	(-14.5 to -0.5) psi (1 to 500) psi (500 to 10 000) psi	65 μpsi/psi 65 μpsi/psi 70 μpsi/psi	Dead Weight Tester
Pressure	(0 to 2) inH ₂ O (2 to 60) inH ₂ O	0.000 35 inH ₂ O 0.009 1 % of reading + 0.000 3 inH ₂ O	Fluke 7250LP Low Pressure Calibrator
Mass Flow (Gas)	(5 to 50 000) SCCM (0.5 to 50) SLPM (50 to 500) SLPM	0.25 % of reading 0.22 % of reading 0.2 % of reading	Mesa Flow System
Air Velocity	30 FPM (40 to 60) FPM (60 to 150) FPM (150 to 275) FPM (275 to 9000) FPM	5.1 % of reading 2.6 % of reading 1.2 % of reading 0.99 % of reading 0.74 % of reading	Wind Tunnel with Pitot Tube
Torque Tools ¹	0.5 ozf·in to 200 ozf·in (5 to 50) lbf·in (50 to 400) lbf·in (400 to 1000) lbf·in (80 to 250) lbf·ft (250 to 600) lbf·ft (600 to 2 000) lbf·ft	0.56 % of reading 0.33 % of reading 0.36 % of reading 0.4 % of reading 0.28 % of reading 0.51 % of reading 0.75 % of reading	Torque Tester
Torque Transducers ¹	0.5 ozf·in to 1 000 lbf·ft	0.08 % of reading	Dead Weight Torque Arms



ANSI National Accreditation Board

Mass and Mass Related

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Graduated Cylinders	(1 to 200) mL (100 to 1 000) mL (600 to 6 000) mL	1.9 µL 3.2 µL 26 µL	Balances
Pipettes	Up to 1 µL (1 to 5) µL (5 to 10) µL (10 to 20) µL (20 to 50) µL (50 to 100) µL (100 to 200) µL (200 to 500) µL (500 to 1 000) µL (1 000 to 10 000) µL (10 to 20) mL	0.041 µL 0.033 µL 0.028 µL 0.034 µL 0.046 µL 0.061 µL 0.27 µL 0.3 µL 0.79 µL 2.7 µL 5.8 µL	Pipette Calibration System
Scales and Balances ^{1,6}	Up to 5 mg (5 to 500) mg 500 mg to 5 g (5 to 10) g (10 to 20) g (20 to 50) g (50 to 100) g (100 to 250) g	0.005 mg 0.006 mg 0.007 mg 0.012 mg 0.014 mg 0.024 mg 0.086 mg 0.092 mg	OIML E2 Class 1 Weights
Scales and Balances ^{1,6}	250 g to 1.1 kg (1.1 to 6.1) kg (6.1 to 33) kg	1.4 mg 9 mg 90 mg	OIML E2 Class 1 Weights
	(0.5 to 2 000) lb	0.01 % of reading	Class 6 Weights
Mass	1 mg to 50 g (50 to 100) g (100 to 250) g (250 to 500) g (500 to 1 kg) (1 to 6) kg (6 to 25) kg	0.01 mg 0.03 mg 0.12 mg 0.17 mg 0.9 mg 9 mg 90 mg	Class 1 Weights
Microindentation Hardness Testers ¹ (Knoop and Vickers)	Repeatability under forces (gf): 100 ≤ HK ≤ 500 HV = 100	2.1 % of Reading 4.1 % of Reading	Indirect Verification to Test Blocks



ANSI National Accreditation Board

Mass and Mass Related

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Brinell Hardness Testers ¹	Repeatability at: 500 kgf		Indirect Verification to Test Blocks
	≤ 100 HBW	0.025 mm	
	≥ 64 HBW	0.025 mm	
	1 500 kgf		
	≤ 257 HBW	0.025 mm	
	≥ 91 HBW	0.03 mm	
Rockwell Hardness Testers ¹	3 000 kgf		Indirect Verification to Test Blocks
	≤ 587 HBW	0.025 mm	
	≥ 186 HBW	0.025 mm	
	HRA Low	1.6 HRA	
	HRA Middle	1.6 HRA	
	HRA High	1.2 HRA	
	HRBW Low	1.6 HRBW	
	HRBW Middle	2.1 HRBW	
	HRBW High	1.6 HRBW	
	HRC Low	1.6 HRC	
	HRC Middle	1.6 HRC	
	HRC High	1.2 HRC	
	HREW Low	1.6 HREW	
	HREW Middle	1.6 HREW	
	HREW High	1.6 HREW	
	HRMW Low	1.6 HRMW	
	HRMW Middle	1.6 HRMW	
	HRMW High	1.6 HRMW	
	HR15N Low	1.7 HR15N	
	HR15N Middle	1.6 HR15N	
	HR15N High	1.3 HR15N	
	HR15TW Low	1.6 HR15TW	
	HR15TW Middle	1.6 HR15TW	
	HR15TW High	1.6 HR15TW	
HR30N Low	1.6 HR30N		
HR30N Middle	1.6 HR30N		
HR30N High	1.4 HR30N		



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Mass and Mass Related

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Rockwell Hardness Testers ¹	HR30TW Low HR30TW Middle HR30TW High HR45N Low HR45N Middle HR45N High	1.6 HR30TW 1.6 HR30TW 1.6 HR30TW 1.6 HR45N 1.6 HR45N 1.6 HR45N	Indirect Verification to Test Blocks
Durometers Spring Force Types A, B, E, O Types C, D, and DO Types M, OO, OOO, OOO-S	(1.3 to 8.05) N (4.445 to 44.5) N (0.294 to 1.932) N	0.023 N 0.06 N 0.002 N	Full Direct Verification Shore Durometer Calibrator Balance
Indenter Angle Indenter Length Indenter Radius	(20 to 40)° (0.049 to 0.198) in (0.05 to 0.1) in	0.004° 220 μin 250 μin	VMM

Thermodynamic

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature - Measure	(-200 to -20) °C (-20 to 120) °C (120 to 200) °C (200 to 300) °C (300 to 660) °C	0.006 2 °C 0.001 7 °C 0.023 °C 0.023 °C 0.024 °C	Fluke 5699 SPRT Fluke 1590 Super Thermometer
Temperature – Source	(-95 to -20) °C (-20 to 120) °C (120 to 425) °C (425 to 660) °C	0.032 °C 0.001 7 °C 0.038 °C 0.063 °C	SPRT Fluke 1590 Super Thermometer With liquid baths and Metrology Well
Radiation (Infrared) Thermometers	(-15 to 0) °C (0 to 100) °C (100 to 200) °C (200 to 350) °C (350 to 500) °C	0.54 °C 0.69 °C 1.1 °C 1.6 °C 2.4 °C	Fluke 4180 and 4181 Black Body Calibrators λ = (8 to 14) μm, ε = (0.9 to 1.0)
Humidity ¹ Source and Measure	(5 to 10) %RH (10 to 50) %RH (50 to 90) %RH (90 to 95) %RH	0.56 %RH 0.5 %RH 0.55 %RH 0.58 %RH	Humidity Indicator

Time and Frequency

Burnsville, MN

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Source ⁴	10 MHz	5 x 10 ⁻¹¹ Hz	SRS FS Rubidium GPS Disciplined Oscillator

DIMENSIONAL MEASUREMENT

2 Dimensional

Burnsville, MN

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Angle	(0.25 to 365)°	0.69m° (12 µin/ in)	Gage Blocks, Gage Amplifier, Sine Bar
Angle	(0.25 to 365)°	0.004°	Coordinate Measuring Machine
Non-contact	(12 x 8 x 4) in	(44 + 1L) µin	Vision System
Roundness/Cylindricity	Up to 150 mm	0.02 µm	Rondcom41c
Surface Finish Analysis	Up to 118 µin (118.1 to 500) µin	0.5 µin + 1 % of nominal 0.6 µin + 1.1 % of nominal	Profilometer, Master Patch

3 Dimensional

Burnsville, MN

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Inspection Contact	(28 x 40 x 28) in	(74 + 4.7L) µin	Coordinate Measuring Machine

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Services performed at satellite laboratory

1208 Allanson Road,
Mundelein, IL 60060
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General Manager: Michael Crosby mcrosby@martincalibration.com

CALIBRATION

Chemical Quantities

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
pH Meters ¹	4 pH 7 pH 10 pH	0.016 pH 0.016 pH 0.016 pH	Buffer Solutions

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Source ¹ fixed point	10V	0.3 µV/V	732B Voltage Standards with Fluke Maps
DC Voltage – Source ¹	0V Up to 1 mV (1 to 10) mV (10 to 100) mV (100 mV to 1) V (1 to 10) V (10 to 100) V (100 to 1 100) V	20 nV 100 nV 22 µV/V + 25 nV 5.3 µV/V 0.5 µV/V 0.31 µV/V 0.35 µV/V 1 µV/V	MI Potentiometer/ Divider & Fluke 5720A Multi Product Calibrator
DC Voltage – Measure ¹	0V Up to 1 mV (1 to 10) mV (10 to 100) mV (100 mV to 1) V (1 to 10) V (10 to 100) V (100 to 1 100) V	20 nV 100 nV 22 µV/V + 25 nV 5.3 µV/V 0.5 µV/V 0.31 µV/V 0.35 µV/V 1 µV/V	Nano Voltmeter Fluke 732B Voltage Standard with MI Potentiometer/ Divider
DC Voltage – Measure ¹	(1.05 to 100) kV	0.1 % of reading	Hipotronics KVM100-A High Voltage Meter



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Source & Measure ¹	Up to 100 nA (0.1 to 1) μ A (1 to 10) μ A (10 to 100) μ A (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A	22 pA 30 μ A/A 6.8 μ A/A 6.2 μ A/A 4.1 μ A/A 4.2 μ A/A 3.9 μ A/A 17 μ A/A	Standard resistors and DMM and Multifunction Calibrator
DC Current – Source & Measure ¹	(1 to 10) A (10 to 20) A (20 to 100) A	80 μ A/A + 80 μ A 80 μ A/A + 800 μ A 80 μ A/A + 40 mA	Fluke 52120A Amplifier
DC Current – Source ¹	(100 to 150) A (150 to 1 025) A	5 mA/A + 20 mA 5.1 mA/A + 0.9 A	Fluke 5520A Multi Product Calibrator with 50-turn Coil
AC Voltage – Source & Measure ¹	(0 to 2.2) mV (10 to 20) Hz (20 to 40) Hz (0.04 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (0.5 to 1) MHz (2.2 to 7) mV (10 to 20) Hz (20 to 40) Hz (0.04 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz (0.5 to 1) MHz	0.035 % of reading + 1.3 μ V 0.037 % of reading + 1.3 μ V 0.04 % of reading + 1.3 μ V 0.025 % of reading + 2 μ V 0.027 % of reading + 2.5 μ V 0.033 % of reading + 4 μ V 0.036 % of reading + 8 μ V 0.02 % of reading + 8 μ V 0.023 % of reading + 1.3 μ V 0.024 % of reading + 1.3 μ V 0.022 % of reading + 1.3 μ V 0.014 % of reading + 2 μ V 0.009 % of reading + 2.5 μ V 0.029 % of reading + 4 μ V 0.055 % of reading + 8 μ V 0.056 % of reading + 8 μ V	Fluke 5790A AC Standard w/ 5720A Multi Product Calibrator
AC Current – Source and Measure ¹	Up to 10 mA (0.01 to 100) kHz (10 to 20) mA (0.01 to 100) kHz (20 to 200) mA (0.01 to 100) kHz	250 μ A/A 250 μ A/A 250 μ A/A	Fluke 5720A Multi Product Calibrator and Fluke 5725A Amplifier w/ A40B Shunts



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source and Measure ¹	(0.2 A to 20) A 0.01 to 1) kHz (1 to 10) kHz (10 to 30) kHz (30 to 100) kHz	250 μ A/A 250 μ A/A 300 μ A/A 350 μ A/A	Fluke 5720A Multi Product Calibrator and Fluke 5725A Amplifier w/ A40B Shunts
AC Current – Source and Measure ¹	(20 to 100) A	0.015 % of reading	Fluke 52120A Amplifier
AC Current – Source ¹ (45 to 65) Hz (65 to 440) Hz	(10 to 16.5) A (16.5 to 150) A (150 to 1 025) A (10 to 16.5) A (16.5 to 150) A (150 to 1 025) A	5.9 mA/A + 30 mA 5.7 mA/A + 25 mA 5.7 mA/A + 0.9 A 11 mA/A + 30 mA 10 mA/A + 0.25 A 13 mA/A + 0.9 A	Fluke 5520A Multi Product Calibrator with 50-turn Coil
AC Current – Measure ¹	Up to 200 μ A (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz 200 μ A to 2 mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz (2 to 20) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz (30 to 100) kHz (20 to 200) mA (1 to 10) Hz 10 Hz to 10 kHz (10 to 30) kHz 200 mA to 2 A 10 Hz to 2 kHz (2 to 10) kHz (10 to 30) kHz	0.62 mA/A 0.54 mA/A 0.94 mA/A 8.4 mA/A 0.6 mA/A 0.54 mA/A 0.94 mA/A 4.2 mA/A 0.6 mA/A 0.54 mA/A 0.94 mA/A 4.2 mA/A 0.57 mA/A 0.49 mA/A 0.83 mA/A 0.83 mA/A 0.93 mA/A 3.2 mA/A	Fluke 8508A Multimeter
AC Current – Measure ¹	(2 to 20) A 10 Hz to 2 kHz (2 to 10) kHz	1 mA/A 2.7 mA/A	Fluke 8508A Multimeter



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source ¹	0.001 Ω	3.5 μΩ/Ω	Standard resistors
	0.01Ω	4.3 μΩ/Ω	
	0.1 Ω	1.5 μΩ/Ω	
	1Ω	0.85 μΩ/Ω	
	10Ω	0.66 μΩ/Ω	
	100 Ω	1.7μΩ/Ω	
	1 kΩ	1.2 μΩ/Ω	
	10 kΩ	2.4 μΩ/Ω	
	100 kΩ	0.57 μΩ/Ω	
	1 MΩ	1.3 μΩ/Ω Ω	
	10 MΩ	14 μΩ/Ω	
	100 MΩ	130 μΩ/Ω	
1 GΩ	0.32 μΩ/Ω		
Resistance – Source ¹	(0.01 to 10) MΩ (0.01 to 10) GΩ	10 μΩ/Ω 0.5 % of reading	Decade resistors with bridge and DMM
Resistance – Source ¹	(10 to 100) GΩ	1.2 % of reading	Decade Resistor
Resistance – Measure ¹ Normal Mode	(10 to 100) μΩ	0.15 % of reading	Decade resistors with bridge and DMM
	(0.1 to 1) mΩ	15 μΩ/Ω	
	(1 to 10) mΩ	5.1 μΩ/Ω	
	(10 o 100) mΩ	1.8 μΩ/Ω	
	(0.1 to 1) Ω	0.92 μΩ/Ω	
	(1 to 10) Ω	0.74 μΩ/Ω	
	(10 to 100) Ω	1.7 μΩ/Ω	
	(0.01 to 1) kΩ	1.3 μΩ/Ω	
	(1 to 10) kΩ	2.4 μΩ/Ω	
	(10 o 100) kΩ	1.1 μΩ/Ω	
	(0.1 to 1) MΩ	8.2 μΩ/Ω	
	(1 to 10) MΩ	21μΩ/Ω	
	(10 to 200) MΩ	72μΩ/Ω + 1kΩ	
	(0.2 to 2) GΩ	0.18 mΩ/Ω + 100 kΩ	
(2 to 20) GΩ	0.67 mΩ/Ω + 10 MΩ		
Resistance – Measure ¹ High Voltage Mode up to 200 V	(2 to 20) MΩ	15 μΩ/Ω + 10 Ω	Decade resistors with bridge and DMM
	(20 to 200) MΩ	60 μΩ/Ω + 1 kΩ	
	200 MΩ to 2 GΩ	0.15 mΩ/Ω + 100 kΩ	
	(2 to 20) GΩ	0.53 mΩ/Ω + 10 MΩ	
Capacitance – Measure ¹	1 pF @ 1 kHz	1.9 mF/F	QuadTech 1730 LCR Meter
	10 pF @ 1 kHz	1.1 mF/F	
	100 pF @ 1kHz	1.2 mF/F	
	1 nF 1kHz	1.2 mF/F	
	1 μF @ 1 kHz	1.2 mF/F	



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source ¹ (fixed values) @ 100 Hz @ 1 kHz	1 pF 1 nF 10 nF 100 nF 1 μF	1.8 mF/F 0.23 mF/F 0.25 mF/F 0.21 mF/F 0.25 mF/F	Standard Capacitors
Capacitance – Source ¹ 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz (10 to 600) Hz 10 Hz to 300 Hz 10 Hz to 150 Hz 10 Hz to 120 Hz 10 Hz to 80 Hz (0 to 50) Hz (0 to 20) Hz (0 to 6) Hz (0 to 2) Hz (0 to 0.6) Hz (0 to 0.2) Hz	0.19 nF to 1.1 nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 110) nF (110 to 330) nF 330 nF to 1.1 μF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF (33 to 110) μF (110 to 330) μF 330 μF to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	15 mF/F 8.4 mF/F 3.6 mF/F 3.6 mF/F 3.7 mF/F 3.6 mF/F 3.6 mF/F 3.6 mF/F 5.1 mF/F 5.6 mF/F 5.6 mF/F 8.7 mF/F 5.5 mF/F 5.5 mF/F 8.5 mF/F 12 mF/F	Fluke 5520A Multi Product Calibrator
Inductance – Measure ¹	100 μH @ 1 kHz 1 mH @ 1 kHz 10 mH @ 1 kHz 100 mH @ 1 kHz 1 H @ 1 kHz	1.2 mH/H	QuadTech 1730 LCR Meter
Inductance – Source ¹	500 μH @ 100 Hz 500 μH @ 1 kHz 2 mH @ 100 Hz 2 mH @ 1 kHz 20 mH @ 100 Hz 20 mH @ 1 kHz	1.2 mH/H 1 mH/H 1.1 mH/H 1 mH/H 1.1 mH/H 1 mH/H	Standard Inductors
Inductance – Source ¹	1 H @ 100 Hz 1 H @ 1 kHz 10 H @ 100 Hz 10 H @ 1 kHz	1 mH/H 1 mH/H 1 mH/H 1 mH/H	Standard Inductors



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ¹ Square Wave Signal 50 Ω at 1 kHz	40 μV to 5 V	1 mV/V	Fluke 9500B/3200/9530 Oscilloscope Calibrator
Square Wave Signal 1 MΩ at 1 kHz	40 μV to 5 V	1 mV/V	
Oscilloscopes ¹ DC Voltage, 50 Ω DC Voltage, 1 MΩ	1 mV to 5 V 1 mV to 200 V	0.26 mV/V 0.25 mV/V	Fluke 9500B/3200/9530 Oscilloscope Calibrator
Leveled Sine Wave Amplitude	5 mV to 5 V	15 mV/V	
Leveled Sine Wave Flatness (relative to 50 kHz)	4.4 mVpp to 5.6 Vpp 0.1 Hz to 300 MHz	43 mV/V	
	(300 to 550) MHz	43 mV/V	
Time Marker 50 Ω Source and Period	4.4 mVpp to 3.3 Vpp 550 MHz to 1.1 GHz	52 mV/V	
	(1.1 to 3.2) GHz	52 mV/V	
Rise/Fall Time - Source	9 ns to 55 s	0.25 μs/s	
Pulse Width - Source	150 ps (1 to 100) ns	27 ps 52 ms/s	
Electrical Simulation of Thermocouple Indicators ¹	Type B		Ectron 1140A Thermocouple Simulator
	(250 to 350) °C	1.1 °C	
	(350 to 445) °C	0.85 °C	
	(445 to 580) °C	0.67 °C	
	(580 to 750) °C	0.52 °C	
	(750 to 1 000) °C	0.43 °C	
	(1 000 to 1 820) °C	0.33 °C	
	Type C		
	(0 to 250) °C	0.23 °C	
	(250 to 1 000) °C	0.18 °C	
	(1 000 to 1 500) °C	0.21 °C	
	(1 500 to 1 800) °C	0.24 °C	
	(1 800 to 2 000) °C	0.27 °C	
(2 000 to 2 250) °C	0.33 °C		
(2 250 to 2 315) °C	0.37 °C		

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type E		Ectron 1140A Thermocouple Simulator
	(-270 to -245) °C	1.4 °C	
	(-245 to -195) °C	0.21 °C	
	(-195 to -155) °C	0.12 °C	
	(-155 to -90) °C	0.09 °C	
	(-90 to 15) °C	0.08 °C	
	(15 to 890) °C	0.07 °C	
	(890 to 1 000) °C	0.08 °C	
	Type J		
	(-210 to -180) °C	0.14 °C	
	(-180 to -120) °C	0.12 °C	
	(-120 to -50) °C	0.09 °C	
	(-50 to 990) °C	0.08 °C	
	(990 to 1 200) °C	0.08 °C	
	Type K		
	(-270 to -255) °C	2.5 °C	
	(-255 to -195) °C	0.81 °C	
	(-195 to -115) °C	0.14 °C	
	(-115 to -55) °C	0.10 °C	
	(-55 to 1 000) °C	0.08 °C	
	(1 000 to 1 372) °C	0.09 °C	
	Type N		
	(-270 to -260) °C	5.8 °C	
	(-260 to -200) °C	1.2 °C	
	(-200 to -140) °C	0.27 °C	
	(-140 to -70) °C	0.17 °C	
	(-70 to 25) °C	0.14 °C	
	(25 to 160) °C	0.12 °C	
(160 to 1 300) °C	0.1 °C		
Type R			
(-50 to -30) °C	0.75 °C		
(-30 to 45) °C	0.63 °C		
(45 to 160) °C	0.46 °C		
(160 to 380) °C	0.35 °C		
(380 to 775) °C	0.3 °C		
(775 to 1 768) °C	0.25 °C		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type S		Ectron 1140A Thermocouple Simulator
	(-50 to -30) °C	0.71 °C	
	(-30 to -45) °C	0.64 °C	
	(-45 to -105) °C	0.46 °C	
	(-105 to 310) °C	0.38 °C	
	(310 to 615) °C	0.33 °C	
	(615 to 1 768) °C	0.3 °C	
	Type T		
	(-270 to -255) °C	2.1 °C	
	(-255 to -240) °C	0.56 °C	
	(-240 to -210) °C	0.35 °C	
	(-210 to -150) °C	0.21 °C	
	(-150 to -40) °C	0.14 °C	
(-40 to 100) °C	0.09 °C		
(100 to 400) °C	0.08 °C		
Electrical Simulation of RTD Indicators ¹	PT 395 100 Ω		Fluke 5520A Multi Product Calibrator
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	(630 to 800) °C	0.27 °C	
	PT 3926 100 Ω		
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	PT 3916 100 Ω		
	(-200 to -190) °C	0.29 °C	
	(-190 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.06 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 260) °C	0.08 °C	
	(260 to 300) °C	0.09 °C	
	(300 to 400) °C	0.11 °C	
(400 to 600) °C	0.12 °C		
(600 to 630) °C	0.27 °C		



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Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicators ¹	PT 385 200 Ω		Fluke 5520A Multi Product Calibrator
	(-200 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.14 °C	
	(300 to 400) °C	0.15 °C	
	(400 to 600) °C	0.16 °C	
	(600 to 630) °C	0.19 °C	
	PT 385 500 Ω		
	(-200 to -80) °C	0.05 °C	
	(-80 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
	(260 to 400) °C	0.09 °C	
	(400 to 600) °C	0.01 °C	
	(600 to 630) °C	0.13 °C	
	PT 395 100 Ω		
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	(630 to 800) °C	0.27 °C	
	PT 3926 100 Ω		
	(-200 to 0) °C	0.06 °C	
	(0 to 100) °C	0.08 °C	
	(100 to 300) °C	0.11 °C	
	(300 to 400) °C	0.12 °C	
	(400 to 630) °C	0.14 °C	
	PT 3916 100 Ω		
	(-200 to -190) °C	0.29 °C	
	(-190 to -80) °C	0.05 °C	
(-80 to 0) °C	0.06 °C		
(0 to 100) °C	0.07 °C		
(100 to 260) °C	0.08 °C		
(260 to 300) °C	0.09 °C		
(300 to 400) °C	0.11 °C		
(400 to 600) °C	0.12 °C		
(600 to 630) °C	0.27 °C		

Electrical – DC/Low Frequency

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicators ¹	PT 385 200 Ω		Fluke 5520A Multi Product Calibrator
	(-200 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.14 °C	
	(300 to 400) °C	0.15 °C	
	(400 to 600) °C	0.16 °C	
	(600 to 630) °C	0.19 °C	
	PT 385 500 Ω		
	(-200 to -80) °C	0.05 °C	
	(-80 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
	(260 to 400) °C	0.09 °C	
	(400 to 600) °C	0.01 °C	
	(600 to 630) °C	0.13 °C	
	PT 385 1 000 Ω		
	(-200 to 0) °C	0.04 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.07 °C	
	(300 to 600) °C	0.08 °C	
(600 to 630) °C	0.27 °C		
PtNi 120 Ω			
(-80 to 100) °C	0.09 °C		
(100 to 260) °C	0.16 °C		
Cu 427 10 Ω			
(-100 to 260) °C	0.35 °C		

Length – Dimensional Metrology

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gage Blocks ²	(0.01 to 1) in (1 to 2) in 4 in	(1.4 + 1.3L) μin (1 + 1.3L) μin 9.4 μin	Gage Blocks Gage Block Comparator
	(5 to 12) in (12 to 20) in	(5 + 2L) μin (2 + 2.8L) μin	Horizontal Measuring Machine
	100 mm (125 to 500) mm	0.17 μm (0.06 + 0.000 6L) μm	Comparison to Primary Master Gage Blocks
Indicators ^{1,2}	(0.000 1 to 6) in	(5+8L) μin	Horizontal Measuring Machine

Length – Dimensional Metrology

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers ^{1,2}	Up to 60 in	$(5+8L) \mu\text{in}$	Gage Blocks
Micrometers OD ^{1,2}	Up to 12 in	$(5+8L) \mu\text{in}$	Gage Blocks, Optical Parallels
Height Measuring Devices ^{1,2}	Up to 36 in (36 to 48) in	$(45 + 2L) \mu\text{in}$ $(7 + 3L) \mu\text{in}$	Gage Blocks
Grind Gages	Up to 100 mm	0.35 mm	Digital Indicator
Coating Thickness Gages ^{1,2}	Up to 0.02 in	$58 \mu\text{in} + 0.6R$	Coating Thickness Standards
Coating Thickness Gage Standards	Up to 0.10 in	21 μin	Horizontal Measuring Machine
External Diameter ^{1,2}	(0.000 1 to 12) in	$(3 + 3L) \mu\text{in}$	Horizontal Measuring Machine
Internal Diameter ^{1,2}	(0.04 to 13) in	$(3 + 3L) \mu\text{in}$	Horizontal Measuring Machine
Thread Rings (Adjustable) Pitch Diameter Tactile Fit (Set to Plug)	Up to 4 in	See footnote ⁵	Thread Setting Plug
Thread Plugs ^{1,2} Pitch Diameter	Up to 8 in Pitch (0.2 to 5) mm	$(87 + 1.9L) \mu\text{in}$	Horizontal Measuring Machine
Major Diameter	Pitch 90 – 4 TPI Up to 4 in	$(3.5 + 4.6L) \mu\text{in}$	Thread Measuring Wires
Optical Comparators ^{1,2} Linear Accuracy	Up to 6 in 6 to 12 in	$(43 + 11L) \mu\text{in}$ $(30 + 7.5L) \mu\text{in}$	Glass Scale
Magnification	(5 to 100) X	350 μin	Glass Scale (Sphere)
Surface Plates ^{1,2} Overall Flatness	Up to 238 inDL	$(25 + 2.9L) \mu\text{in}$	Laser System
Local Area Flatness	Up to 238 inDL	34 μin	Repeat-O-Meter
Surface Finish Artifacts	Up to 500 μin	2.4 μin	Profilometer, Master Patch
Profilometers ¹	Up to 500 μin	3.1 μin	Master Patch



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Length – Dimensional Metrology

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Optical Flats Parallelism Flatness	Up to 6 inD (0 to 80) μ in	2.7 μ in 3.5 μ in	Gage Block Comparator, Master Flat
CMMs ^{1,2} Linearity	(0 to 144) in	(25 + 2.4L) μ in	Laser Measuring System
Volumetric Repeatability	(6 to 24) in (0.5 to 2) in	66 μ in 45 μ in	Ball Bar, CMM Sphere
VMMs ^{1,2}	Linearity	(32 + 4.1L) μ in	Glass Scales
Graduated Scales ^{1,2} Glass, Steel, Tape	Up to 12 in (1 to 200) ft	(40 + 1L) μ in (10+ 3L) μ in	Laser Measuring System
Horizontal Measuring Systems ^{1,2}	Up to 8 in 8 to 60 in	(6 + 1.7L) μ in (3 + 2.5L) μ in	Gage Blocks
Protractors	(0 to 90) °	0.16 °	Sine Bar, Gage Blocks
Length Standards ²	(1 to 60) in	(3.4 + 3.5L) μ in	Horizontal Measuring System
Micrometers - Inside ²	Up to 8 in 8 to 60 in	(6 + 1.7L) μ in (3 + 2.5L) μ in	Horizontal Measuring System

Mass and Mass Related

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force ¹ Source and Measure	(0.035 to 16) ozf (1 to 10) lbf (10 to 50) lbf (50 to 500) lbf	0.018 % of reading + 0.21 μ ozf 0.018 % of reading + 0.33 μ lbf 0.018 % of reading + 9.3 mlbf 0.036 % of reading + 5.3 mlbf	Dead Weight
	(500 to 1 000) lbf (10 to 100) klbf	0.05 % of reading 0.06 % of reading	Load Cells, Class AA
Force ¹ Source and Measure	(30 000 to 400 000) lbf	0.29 % of applied value	Load Cells, Class A (compression only)
Pressure ¹	(10 to 17) psia	0.000 4 psi	Pressure Calibrator
Pressure ¹	(-14.5 to -0.5) psi (1 to 16 000) psi	65 μ psi/psi 65 μ psi/psi	Deadweight Tester



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Mass and Mass Related

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Torque Tools ¹	0.5 ozf·in to 200 ozf·in (5 to 50) lbf·in (50 to 400) lbf·in (400 to 1000) lbf·in (80 to 250) lbf·ft (250 to 600) lbf·ft (600 to 1 000) lbf·ft	0.56 % of reading 0.33 % of reading 0.36 % of reading 0.4 % of reading 0.28 % of reading 0.51 % of reading 0.75 % of reading	Torque Tester
Scales and Balances ^{1,6}	Up to 5 mg (5 to 500) mg 500 mg to 5 g (5 to 10) g (10 to 20) g (20 to 50) g (50 to 100) g (100 to 250) g 250 g to 1.1 kg (1.1 to 6.1) kg (6.1 to 33) kg	0.005 mg 0.006 mg 0.007 mg 0.012 mg 0.014 mg 0.024 mg 0.086 mg 0.092 mg 1.4 mg 9 mg 90 mg	OIML E2 Class 1 Weights
Scales and Balances ^{1,6}	(0.5 to 2 000) lb	0.01 % of reading	Class 6 Weights
Indirect Verification of Microindentation Hardness Testers ¹ (Knoop and Vickers)	Repeatability under forces (gf): 100 ≤ HK ≤ 500 HV = 100	2.1 % of Reading 4.1 % of Reading	Indirect Verification to Test Blocks
Brinell Hardness Testers ¹ Repeatability	500 kgf ≤ 100 HBW ≥ 64 HBW 1 500 kgf ≤ 257 HBW ≥ 91 HBW 3 000 kgf ≤ 587 HBW ≥ 186 HBW	0.025 mm 0.025 mm 0.025 mm 0.03 mm 0.025 mm 0.025 mm	Indirect Verification to Test Blocks



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Mass and Mass Related

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Rockwell Hardness Testers ¹	HRA Low	1.6 HRA	Indirect Verification to Test Blocks
	HRA Middle	1.6 HRA	
	HRA High	1.2 HRA	
	HRBW Low	1.6 HRBW	
	HRBW Middle	2.1 HRBW	
	HRBW High	1.6 HRBW	
	HRC Low	1.6 HRC	
	HRC Middle	1.6 HRC	
	HRC High	1.2 HRC	
	HREW Low	1.6 HREW	
	HREW Middle	1.6 HREW	
	HREW High	1.6 HREW	
	HRMW Low	1.6 HRMW	
	HRMW Middle	1.6 HRMW	
	HRMW High	1.6 HRMW	
	HR15N Low	1.7 HR15N	
	HR15N Middle	1.6 HR15N	
	HR15N High	1.3 HR15N	
	HR15TW Low	1.6 HR15TW	
	HR15TW Middle	1.6 HR15TW	
	HR15TW High	1.6 HR15TW	
	HR30N Low	1.6 HR30N	
	HR30N Middle	1.6 HR30N	
	HR30N High	1.4 HR30N	
HR30TW Low	1.6 HR30TW		
HR30TW Middle	1.6 HR30TW		
HR30TW High	1.6 HR30TW		
HR45N Low	1.6 HR45N		
HR45N Middle	1.6 HR45N		
HR45N High	1.6 HR45N		



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Mass and Mass Related

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Durometers Spring Force Types A, B, E, O Types C, D, and DO Types OO, OOO, OOO-S	(1.3 to 8.05) N (4.445 to 44.5) N (0.294 to 1.932) N	0.023 N 0.06 N 0.002 N	Shore Durometer Calibrator Balance
Indenter Angle Indenter Length Indenter Radius	(20 to 40) ° (0.049 to 0.198) in (0.05 to 0.1) in	0.05 ° 220 μin 250 μin	VMM

Thermodynamic

Mundelein, IL

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature - Measure	(-200 to -20) °C (-20 to 120) °C (120 to 200) °C (200 to 300) °C (300 to 600) °C	0.006 2 °C 0.001 7 °C 0.023 °C 0.023 °C 0.024 °C	Fluke 5699 SPRT Fluke 1590 Super Thermometer
Temperature – Source	(-20 to 120) °C (120 to 425) °C (425 to 660) °C	0.001 7 °C 0.038 °C 0.063 °C	SPRT Fluke 1590 Super Thermometer With liquid baths and Metrology Well
Radiation (Infrared) Thermometers	(50 to 100) °C (100 to 200) °C (200 to 250) °C (250 to 300) °C (300 to 400) °C (400 to 500) °C	0.8 °C 0.93 °C 0.96 °C 1 °C 1.1 °C 1.2 °C	Black Body Calibrator Monitored with a PRT $\epsilon = 0.95, \lambda = (8 \text{ to } 14) \mu\text{m}$
Humidity ¹ Source and Measure	(20 to 50) %RH (50 to 90) %RH	1.6 %RH 2.1 %RH	Humidity Indicator

DIMENSIONAL MEASUREMENT

2 Dimensional

Mundelein, IL

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Non-contact	(6 x 8) in	$(239 + 1.4L) \mu\text{in}$	Vision System
Surface Finish Analysis	Up to 500 μin	2.4 μin	Profilometer, Master Patch

3 Dimensional

Mundelein, IL

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Inspection Contact	(16 x 18 x 14) in	$(209 + 1.2L) \mu\text{in}$	Coordinate Measuring Machine

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Services performed at satellite laboratory

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General Manager: Kevin Gifford kgifford@martincalibration.com

CALIBRATION AND DIMENSIONAL MEASUREMENT

CALIBRATION

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Source ¹	Up to 330 mV 330 mV to 3.3 V (3.3 to 33) V (33 to 330) V (330 to 1 020) V	21 μ V/V + 1 μ V 11 μ V/V + 2 μ V 13 μ V/V + 20 μ V 18 μ V/V + 150 μ V 18 μ V/V + 1.5 mV	5522A Multi Product Calibrator
DC Voltage – Measure ¹	Up to 100 mV 100 mV to 1 V (1 to 10) V (10 to 100) V 100 V to 1 kV	12 μ V/V + 0.3 μ V 10 μ V/V + 0.3 μ V 10 μ V/V + 0.5 μ V 13 μ V/V + 30 μ V 13 μ V/V + 100 μ V	Keysight 3458A Multimeter
DC Current – Source ¹	Up to 330 μ A 330 μ A to 3.3 mA (3.3 to 33) mA (33 to 330) mA 330 mA to 1.1 A (1.1 to 3) A (3 to 11) A (11 to 20) A	151 μ A/A + 20 nA 101 μ A/A + 50 nA 101 μ A/A + 250 nA 102 μ A/A + 2.5 μ A 201 μ A/A + 40 μ A 386 μ A/A + 40 μ A 504 μ A/A + 0.5 mA 1 mA/A + 0.75 mA	5522A Multi Product Calibrator
DC Current – Measure ¹	(10 to 100) μ A 100 μ A to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A	29 μ A/A + 0.8 nA 27 μ A/A + 5 nA 28 μ A/A + 50 nA 46 μ A/A + 0.5 μ A 121 μ A/A + 10 μ A	Keysight 3458A Multimeter
AC Voltage – Source	Up to 33 mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	806 μ V/V + 6 μ V 176 μ V/V + 6 μ V 220 μ V/V + 6 μ V 1 mV/V + 6 μ V 3.5 mV/V + 12 μ V 8 mV/V + 50 μ V	5522A Multi Product Calibrator



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source	(33 to 330) mV		5522A Multi Product Calibrator
	(10 to 45) Hz	302 $\mu\text{V/V} + 8 \mu\text{V}$	
	45 Hz to 10 kHz	148 $\mu\text{V/V} + 8 \mu\text{V}$	
	(10 to 20) kHz	163 $\mu\text{V/V} + 8 \mu\text{V}$	
	(20 to 50) kHz	353 $\mu\text{V/V} + 8 \mu\text{V}$	
	(50 to 100) kHz	804 $\mu\text{V/V} + 32 \mu\text{V}$	
	(100 to 500) kHz	2 mV/V + 70 μV	
	330 mV to 3.3 V		
	(10 to 45) Hz	302 $\mu\text{V/V} + 50 \mu\text{V}$	
	45 Hz to 10 kHz	153 $\mu\text{V/V} + 60 \mu\text{V}$	
	(10 to 20) kHz	192 $\mu\text{V/V} + 60 \mu\text{V}$	
	(20 to 50) kHz	302 $\mu\text{V/V} + 50 \mu\text{V}$	
	(50 to 100) kHz	703 $\mu\text{V/V} + 125 \mu\text{V}$	
	(100 to 500) kHz	2.4 mV/V + 0.6 mV	
	(3.3 to 33) V		
	(10 to 45) Hz	302 $\mu\text{V/V} + 650 \mu\text{V}$	
	45 Hz to 10 kHz	153 $\mu\text{V/V} + 600 \mu\text{V}$	
	(10 to 20) kHz	242 $\mu\text{V/V} + 600 \mu\text{V}$	
	(20 to 50) kHz	353 $\mu\text{V/V} + 600 \mu\text{V}$	
	(50 to 100) kHz	903 $\mu\text{V/V} + 1.6 \text{ mV}$	
AC Voltage – Measure	(33 to 330) V		Keysight 3458A Multimeter
	45 Hz to 1 kHz	194 $\mu\text{V/V} + 2 \text{ mV}$	
	(1 to 10) kHz	204 $\mu\text{V/V} + 6 \text{ mV}$	
	(10 to 20) kHz	253 $\mu\text{V/V} + 6 \text{ mV}$	
	(20 to 50) kHz	314 $\mu\text{V/V} + 6 \text{ mV}$	
	(50 to 100) kHz	2 mV/V + 50 mV	
	(330 to 1020) V		
	45 Hz to 1 kHz	302 $\mu\text{V/V} + 10 \text{ mV}$	
	(1 to 5) kHz	252 $\mu\text{V/V} + 10 \text{ mV}$	
	(5 to 10) kHz	302 $\mu\text{V/V} + 10 \text{ mV}$	



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure	(10 to 100) mV		Keysight 3458A Multimeter
	(1 to 40) Hz	70 $\mu\text{V}/\text{V} + 4 \mu\text{V}$	
	40 Hz to 1 kHz	83.8 $\mu\text{V}/\text{V} + 2 \mu\text{V}$	
	(1 to 20) kHz	157 $\mu\text{V}/\text{V} + 2 \mu\text{V}$	
	(20 to 50) kHz	308 $\mu\text{V}/\text{V} + 2 \mu\text{V}$	
	(50 to 100) kHz	878 $\mu\text{V}/\text{V} + 2 \mu\text{V}$	
	(100 to 300) kHz	3.1 mV/V + 10 μV	
	300 kHz to 1 MHz	10 mV/V + 10 μV	
	(1 to 2) MHz	15 mV/V + 10 μV	
	100 mV to 1 V		
	(1 to 40) Hz	70 $\mu\text{V}/\text{V} + 40 \mu\text{V}$	
	40 Hz to 1 kHz	80.7 $\mu\text{V}/\text{V} + 20 \mu\text{V}$	
	(1 to 20) kHz	154 $\mu\text{V}/\text{V} + 20 \mu\text{V}$	
	(20 to 50) kHz	327 $\mu\text{V}/\text{V} + 20 \mu\text{V}$	
	(50 to 100) kHz	825 $\mu\text{V}/\text{V} + 20 \mu\text{V}$	
	(100 to 300) kHz	3.1 mV/V + 0.1 mV	
	300 kHz to 1 MHz	10 mV/V + 0.1 mV	
	(1 to 2) MHz	15 mV/V + 0.1 mV	
	(1 to 10) V		
	(1 to 40) Hz	77 $\mu\text{V}/\text{V} + 400 \mu\text{V}$	
	40 Hz to 1 kHz	81 $\mu\text{V}/\text{V} + 200 \mu\text{V}$	
	(1 to 20) kHz	154 $\mu\text{V}/\text{V} + 200 \mu\text{V}$	
	(20 to 50) kHz	324 $\mu\text{V}/\text{V} + 200 \mu\text{V}$	
	(50 to 100) kHz	816 $\mu\text{V}/\text{V} + 200 \mu\text{V}$	
	(100 to 300) kHz	3.1 mV/V + 1 mV	
	300 kHz to 1 MHz	10 mV/V + 1 mV	
	(1 to 2) MHz	15 mV/V + 1 mV	
	(10 to 100) V		
(1 to 40) Hz	200 $\mu\text{V}/\text{V} + 4 \text{ mV}$		
40 Hz to 1 kHz	205 $\mu\text{V}/\text{V} + 2 \text{ mV}$		
(1 to 20) kHz	215 $\mu\text{V}/\text{V} + 2 \text{ mV}$		
(20 to 50) kHz	358 $\mu\text{V}/\text{V} + 2 \text{ mV}$		
(50 to 100) kHz	1.2 mV/V + 2 mV		
(100 to 300) kHz	4 mV/V + 2 mV		
300 kHz to 1 MHz	15 mV/V + 10 mV		
(100 to 1 000) V			
(1 to 40) Hz	400 $\mu\text{V}/\text{V} + 40 \text{ mV}$		
40 Hz to 1 kHz	405 $\mu\text{V}/\text{V} + 20 \text{ mV}$		
(1 to 20) kHz	600 $\mu\text{V}/\text{V} + 20 \text{ mV}$		
(20 to 50) kHz	1.2 mV/V + 20 mV		
(50 to 100) kHz	3 mV/V + 20 mV		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Measure	Up to 100 μ A		Keysight 3458A Multimeter
	(10 to 20) Hz	4 mA/A + 30 nA	
	(20 to 45) Hz	1.5 mA/A + 30 nA	
	(45 to 100) Hz	605 μ A/A + 30 nA	
	100 Hz to 1 kHz	610 μ A/A + 30 nA	
	100 μ A to 1 mA		
	(10 to 20) Hz	4 mA/A + 0.2 μ A	
	(20 to 45) Hz	1.5 mA/A + 0.2 μ A	
	(45 to 100) Hz	605 μ A/A + 0.2 μ A	
	100 Hz to 5 kHz	325 μ A/A + 0.2 μ A	
	(5 to 20) kHz	605 μ A/A + 0.2 μ A	
	(20 to 50) kHz	4 mA/A + 0.4 μ A	
	(50 to 100) kHz	5.5 mA/A + 1.5 μ A	
	(1 to 10) mA		
	(10 to 20) Hz	4 mA/A + 2 μ A	
	(20 to 45) Hz	1.5 mA/A + 2 μ A	
	(45 to 100) Hz	605 μ A/A + 2 μ A	
	100 Hz to 5 kHz	325 μ A/A + 2 μ A	
	(5 to 20) kHz	605 μ A/A + 2 μ A	
	(20 to 50) kHz	4 mA/A + 4 μ A	
	(50 to 100) kHz	5.5 mA/A + 15 μ A	
	(10 to 100) mA		
	(10 to 20) Hz	4 mA/A + 20 μ A	
	(20 to 45) Hz	1.5 mA/A + 20 μ A	
	(45 to 100) Hz	605 μ A/A + 20 μ A	
	100 Hz to 5 kHz	325 μ A/A + 20 μ A	
	(5 to 20) kHz	605 μ A/A + 20 μ A	
	(20 to 50) kHz	4 mA/A + 40 μ A	
	(50 to 100) kHz	5.5 mA/A + 150 μ A	
	100 mA to 1 A		
(10 to 20) Hz	4 mA/A + 0.2 mA		
(20 to 45) Hz	1.6 mA/A + 0.2 mA		
(45 to 100) Hz	805 μ A/A + 0.2 mA		
100 Hz to 5 kHz	1 mA/A + 0.2 mA		
(5 to 20) kHz	3 mA/A + 0.2 mA		
(20 to 50) kHz	10 mA/A + 0.4 mA		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source	(29 to 330) μ A		5522A Multi Product Calibrator
	(10 to 20) Hz	2 mA/A + 0.1 μ A	
	(20 to 45) Hz	1.5 mA/A + 0.1 μ A	
	45 Hz to 1 kHz	1.3 mA/A + 0.1 μ A	
	(1 to 5) kHz	3 mA/A + 0.15 μ A	
	(5 to 10) kHz	8 mA/A + 0.2 μ A	
	(10 to 30) kHz	16 mA/A + 0.4 μ A	
	(0.33 to 3.3) mA		
	(10 to 20) Hz	2 mA/A + 0.15 μ A	
	(20 to 45) Hz	1.3 mA/A + 0.15 μ A	
	45 Hz to 1 kHz	1 mA/A + 0.15 μ A	
	(1 to 5) kHz	2 mA/A + 0.2 μ A	
	(5 to 10) kHz	5.1 mA/A + 0.3 μ A	
	(10 to 30) kHz	10 mA/A + 0.6 μ A	
	(3.3 to 33) mA		
	(10 to 20) Hz	1.8 mA/A + 2 μ A	
	(20 to 45) Hz	910 μ A/A + 2 μ A	
	45 Hz to 1 kHz	423 μ A/A + 2 μ A	
	(1 to 5) kHz	813 μ A/A + 2 μ A	
	(5 to 10) kHz	2 mA/A + 3 μ A	
	(10 to 30) kHz	4.1 mA/A + 4 μ A	
	(33 to 330) mA		
	(10 to 20) Hz	1.8 mA/A + 20 μ A	
	(20 to 45) Hz	909 μ A/A + 20 μ A	
	45 Hz to 1 kHz	417 μ A/A + 20 μ A	
	(1 to 5) kHz	1 mA/A + 50 μ A	
	(5 to 10) kHz	2 mA/A + 100 μ A	
	(10 to 30) kHz	4.1 mA/A + 200 μ A	
(0.33 to 1.1) A			
(10 to 45) Hz	1.8 mA/A + 100 μ A		
45 Hz to 1 kHz	512 μ A/A + 100 μ A		
(1 to 5) kHz	6 mA/A + 1 mA		
(5 to 10) kHz	25 mA/A + 5 mA		
(1.1 to 3) A			
(10 to 45) Hz	1.8 mA/A + 100 μ A		
45 Hz to 1 kHz	664 μ A/A + 100 μ A		
(1 to 5) kHz	6 mA/A + 1 mA		
(5 to 10) kHz	25 mA/A + 5 mA		

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source	(3 to 11) A (45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz (11 to 20.5) A (45 to 100) Hz 100 Hz to 1 kHz (1 to 5) kHz	1.8 mA/A + 100 μA 664 μA/A + 100 μA 6 mA/A + 1 mA 1.2 mA/A + 5 mA 1.5 mA/A + 5 mA 30 mA/A + 5 mA	5522A Multi Product Calibrator
Resistance - Source ¹	Up to 11 Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω 330 Ω to 1.1 kΩ (1.1 to 3.3) kΩ (3.3 to 11) kΩ (11 to 33) kΩ (33 to 110) kΩ (110 to 330) kΩ 330 kΩ to 1.1 MΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ (11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ 330 MΩ to 1.1 GΩ	36 μΩ/Ω 26 μΩ/Ω 23 μΩ/Ω 23 μΩ/Ω 23 μΩ/Ω 23 μΩ/Ω 23 μΩ/Ω 23 μΩ/Ω 24 μΩ/Ω 26 μΩ/Ω 26 μΩ/Ω 42 μΩ/Ω 110 μΩ/Ω 201 μΩ/Ω 400 μΩ/Ω 2.5 mΩ/Ω 12 mΩ/Ω	5522A Multi Product Calibrator
Resistance – Measure ¹	100 μΩ to 10 Ω (10 to 100) Ω 100 Ω to 1 kΩ (1 to 10) kΩ (10 to 100) kΩ 100 kΩ to 1 MΩ (1 to 10) MΩ (10 to 100) MΩ	20 μΩ/Ω + 50 μΩ 17 μΩ/Ω + 5 μΩ 15 μΩ/Ω + 500 μΩ 15 μΩ/Ω + 5 mΩ 15 μΩ/Ω + 50 mΩ 20 μΩ/Ω + 2 Ω 83 μΩ/Ω + 100 Ω 820 μΩ/Ω + 1 kΩ	Keysight 3458A Multimeter
Capacitance – Source	10 Hz to 10 kHz (220 to 400) pF (0.4 to 1.1) nF 10 Hz to 3 kHz (1.1 to 3.3) nF	6.4 mF/F + 10 pF 5.3 mF/F + 10 pF 5.1 mF/F + 10 pF	5522A Multi Product Calibrator



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source	10 Hz to 1 kHz (3.3 to 11) nF	2.6 mF/F + 10 pF	5522A Multi Product Calibrator
	(11 to 33) nF	2.6 mF/F + 100 pF	
	(33 to 110) nF	2.6 mF/F + 100 pF	
	(110 to 330) nF	2.6 mF/F + 300 pF	
	(10 to 600) Hz (0.33 to 1.1) μF	2.6 mF/F + 1 nF	
	(10 to 300) Hz (1.1 to 3.3) μF	2.6 mF/F + 3 nF	
	(10 to 150) Hz (3.3 to 11) μF	2.6 mF/F + 10 nF	
	(10 to 120) Hz (11 to 33) μF	4.1 mF/F + 30 nF	
	(10 to 80) Hz (33 to 110) μF	4.7 mF/F + 0.1 μF	
	(0 to 50) Hz (110 to 330) μF	4.6 mF/F + 0.3 μF	
	(0 to 20) Hz (0.33 to 1.1) mF	4.6 mF/F + 1 μF	
	(0 to 6) Hz (1.1 to 3.3) mF	4.5 mF/F + 3 μF	
	(0 to 2) Hz (3.3 to 11) mF	4.5 mF/F + 10 μF	
	(0 to 0.6) Hz (11 to 33) mF	7.5 mF/F + 30 μF	
	(0 to 0.2) Hz (33 to 110) mF	11 mF/F + 100 μF	
Electrical Simulation of Thermocouple Indicators ¹	Type B (600 to 800) °C	0.44 °C	5522A Multi Product Calibrator
	(800 to 1 000) °C	0.34 °C	
	(1 000 to 1 550) °C	0.3 °C	
	(1 550 to 1 820) °C	0.33 °C	
	Type C (0 to 150) °C	0.3 °C	
	(150 to 650) °C	0.26 °C	
	(650 to 1 000) °C	0.31 °C	
	(1 000 to 1 800) °C	0.5 °C	
	(1 800 to 2 316) °C	0.84 °C	



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Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type E		5522A Multi Product Calibrator
	(-250 to -100) °C	0.5 °C	
	(-100 to -25) °C	0.16 °C	
	(-25 to 350) °C	0.14 °C	
	(350 to 650) °C	0.16 °C	
	(650 to 1 000) °C	0.21 °C	
	Type J		
	(-210 to -100) °C	0.27 °C	
	(-100 to - 30) °C	0.16 °C	
	(-30 to 150) °C	0.14 °C	
	(150 to 760) °C	0.17 °C	
	(760 to 1 200) °C	0.23 °C	
	Type K		
	(-200 to -100) °C	0.33 °C	
	(-100 to -25) °C	0.18 °C	
	(-25 to 120) °C	0.16 °C	
	(120 to 1 000) °C	0.26 °C	
	(1 000 to 1 372) °C	0.4 °C	
	Type L		
	(-200 to -100) °C	0.37 °C	
	(-100 to 800) °C	0.26 °C	
	(800 to 900) °C	0.17 °C	
	Type N		
	(-200 to -100) °C	0.4 °C	
(-100 to - 25) °C	0.22 °C		
(-25 to 120) °C	0.19 °C		
(120 to 410) °C	0.18 °C		
(410 to 1 300) °C	0.27 °C		
Type R			
(0 to 250) °C	0.57 °C		
(250 to 400) °C	0.35 °C		
(400 to 1 000) °C	0.33 °C		
(1 000 to 1 767) °C	0.4 °C		
Type S			
(0 to 250) °C	0.47 °C		
(250 to 400) °C	0.36 °C		
(400 to 1 000) °C	0.37 °C		
(1 000 to 1 767) °C	0.46 °C		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators ¹	Type T		5522A Multi Product Calibrator
	(-250 to -150) °C	0.63 °C	
	(-150 to 0) °C	0.24 °C	
	(0 to 120) °C	0.16 °C	
	(120 to 400) °C	0.14 °C	
	Type U		
(-200 to 0) °C	0.56 °C		
(0 to 600) °C	0.27 °C		
Electrical Simulation of RTD Indicators ¹	Pt 385, 100 Ω		5522A Multi Product Calibrator
	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 300) °C	0.09 °C	
	(300 to 400) °C	0.1 °C	
	(400 to 630) °C	0.12 °C	
	(630 to 800) °C	0.23 °C	
	Pt 3926, 100 Ω		
	(-200 to -80) °C	0.05 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.07 °C	
	(100 to 300) °C	0.09 °C	
	(300 to 400) °C	0.10 °C	
	(400 to 630) °C	0.12 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.25 °C	
	(-190 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.06 °C	
	(100 to 260) °C	0.07 °C	
(260 to 300) °C	0.08 °C		
(300 to 400) °C	0.09 °C		
(400 to 600) °C	0.1 °C		
(600 to 630) °C	0.23 °C		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicators ¹	Pt 385, 200 Ω		5522A Multi Product Calibrator
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.04 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.12 °C	
	(300 to 400) °C	0.13 °C	
	(400 to 600) °C	0.14 °C	
	(600 to 630) °C	0.16 °C	
	Pt 385, 500 Ω		
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.05 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.06 °C	
	(260 to 300) °C	0.08 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 600) °C	0.09 °C	
	(600 to 630) °C	0.11 °C	
	Pt 385, 1 000 Ω		
	(-200 to -80) °C	0.03 °C	
	(-80 to 0) °C	0.03 °C	
(0 to 100) °C	0.04 °C		
(100 to 260) °C	0.05 °C		
(260 to 300) °C	0.06 °C		
(300 to 400) °C	0.07 °C		
(400 to 600) °C	0.07 °C		
(600 to 630) °C	0.23 °C		
PtNi 385, 120 Ω (Ni120)			
(-80 to 0) °C	0.08 °C		
(0 to 100) °C	0.08 °C		
(100 to 260) °C	0.14 °C		
Cu 427, 10 Ω			
(100 to 260) °C	0.3 °C		

Length – Dimensional Metrology

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Indicators ^{1,2}	(0.000 1 to 6) in	(8+3L) μin	Horizontal Measuring Machine

Length – Dimensional Metrology

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers ^{1,2}	Up to 60 in	$(5+8L) \mu\text{in}$	Gage Blocks
Micrometers OD ^{1,2}	Up to 60 in Anvil Flatness	$(5+8L) \mu\text{in}$ 4 μin	Gage Blocks Optical Parallels
Height Measuring Devices ^{1,2}	Up to 36 in (36 to 48) in	$(45 + 2L) \mu\text{in}$ $(7 + 3L) \mu\text{in}$	Gage Blocks
External Diameter ^{1,2}	(0.000 1 to 6) in	$(8+3L) \mu\text{in}$	Horizontal Measuring Machine
Internal Diameter ^{1,2}	(0.04 to 13) in	$(8+3L) \mu\text{in}$	Horizontal Measuring Machine
Thread Plugs ^{1,2} Pitch Diameter	Up to 8 in Pitch (0.2 to 5) mm	$(87 + 1.9L) \mu\text{in}$	Horizontal Measuring Machine
Major Diameter	Pitch 90 – 4 TPI Up to 4 in	$(8+3L) \mu\text{in}$	Thread Measuring Wires
Thread Rings (Adjustable) Pitch Diameter Tactile Fit (Set to Plug)	Up to 4 in	See footnote ⁵	Thread Setting Plug
Optical Comparators ^{1,2} Linear Accuracy	Up to 6 in 6 to 12 in	$(43 + 11L) \mu\text{in}$ $(30 + 7.5L) \mu\text{in}$	Glass Scale
Magnification	5X to 100X	350 μin	Glass Scale (Sphere)
Surface Plates ^{1,2} Overall Flatness	Up to 238 inDL	$(25 + 2.9L) \mu\text{in}$	Laser System
Local Area Flatness	Up to 238 inDL	34 μin	Repeat-O-Meter
CMMs ^{1,2}	(0 to 144) in	$(25 + 2.4L) \mu\text{in}$	Laser Measuring System
VMMs ^{1,2}	Up to 6 in	$(32 + 4.1L) \mu\text{in}$	Glass Scales
Horizontal Measuring Systems ^{1,2}	Up to 8 in of Travel (8 to 60) in	$(6 + 1.7L) \mu\text{in}$ $(3 + 2.5L) \mu\text{in}$	Gage Blocks
Feeler/Thickness Gages ²	Up to 0.2 in	$(4.3 + 3L) \mu\text{in}$	Horizontal Measuring System
Indicator Calibrator ² Linearity	Up to 6 in	60 $\mu\text{in} + 0.6R$	Horizontal Measuring System
Groove Micrometers ²	Up to 12 in	$(44 + 2.6L) \mu\text{in} + 0.6R$	Gage Blocks

Length – Dimensional Metrology

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Microscopes, Stereo Reticle Linearity	Up to 2 in	870 μ in	Stage Micrometer
Microscopes – Toolmakers ² Scale Linearity	Up to 4 in	(774 + 70L) μ in + 0.6R	Stage Micrometer
Length Standards ²	(1 to 60) in	(3.4 + 3.5L) μ in	Horizontal Measuring System
Micrometers – Inside ²	Up to 8 in 8 to 60 in	(6 + 1.7L) μ in (3 + 2.5L) μ in	Horizontal Measuring System
Parallels ² Steel Granite	Up to 18 in	(96.3 + 1.8L) μ in (48.6 + 0.7L) μ in	Electronic Amplifier with Probe, Surface Plate
Thickness Gages ² Dial Digital	Up to 1 in	410 μ in + 0.6R 44 μ in + 0.6R	Gage Blocks
Thread Micrometers ² (Screw Thread, Pitch Point) Linearity Anvil Wear	Up to 12 in	(44 + 2.6L) μ in + 0.6R 690 μ in	Gage Blocks Thread Setting Plug

Mass and Mass Related

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force ¹ Source	(0.035 to 16) ozf (1 to 10) lbf (10 to 50) lbf (50 to 500) lbf	0.018 % of reading + 0.21 μ ozf 0.018 % of reading + 0.33 μ lbf 0.018 % of reading + 9.3 mlbf 0.036 % of reading + 5.3 mlbf	Dead Weight
Pressure ¹	(-15 to 30) psig (0 to 1) inH ₂ O (0.036 to 1) psig (0 to 100) psia (100 to 300) psig (300 to 1 000) psig (1 000 to 10 000) psig	19 mpsi 0.003 5 inH ₂ O 1.3 mpsi 0.07 psi 0.12 psi 0.4 psi 4 psi	Pressure Calibrator



ANSI National Accreditation Board

Mass and Mass Related

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Torque Tools ¹	(5 to 50) lbf·in (50 to 400) lbf·in (400 to 1000) lbf·in (80 to 250) lbf·ft (250 to 600) lbf·ft (600 to 2 000) lbf·ft	0.33 % of reading 0.36 % of reading 0.4 % of reading 0.28 % of reading 0.51 % of reading 0.75 % of reading	Torque Tester
Torque Transducers ¹	0.5 ozf·in to 1 000 lbf·ft	0.08 % of reading	Dead Weight Torque Arms
Scales and Balances ^{1,6}	(0 to 500) mg 500 mg to 5 g (5 to 10) g (10 to 30) g (30 to 50) g (50 to 100) g (100 to 200) g (200 to 300) g 300 g to 1 kg (1 to 2) kg (2 to 3) kg	0.01 mg 0.034 mg 0.05 mg 0.074 mg 0.12 mg 0.25 mg 0.5 mg 0.75 mg 2.5 mg 5 mg 7.5 mg	Class 1 Weights
Scales and Balances ^{1,6}	(3 to 5) kg (5 to 10) kg (10 to 20) kg (20 to 25) kg (25 to 30) kg	12 mg 25 mg 50 mg 62 mg 75 mg	Class 1 Weights
Scales and Balances ^{1,6}	(0.5 to 1 000) lb	0.01 % of reading	Class 6 Weights

Thermodynamic

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature – Measure ¹	(-20 to 100) °C (100 to 425) °C (425 to 500) °C	0.058 °C 0.069 °C 0.086 °C	Digital Temperature Gage
Humidity- Measure ¹	(10 to 40) %RH (40 to 90) %RH (90 to 100) %RH	1.1 %RH 1.3 %RH 1.9 %RH	Humidity Indicator

Time and Frequency

Eau Claire, WI

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Source ⁴	1 MHz	2.5×10^{-5} Hz	5522A Multi Product Calibrator

DIMENSIONAL MEASUREMENT

2 Dimensional

Eau Claire, WI

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Non-contact	(15.4 x 10.8) in	$(126 + 12L) \mu\text{in}$	Vision System

3 Dimensional

Eau Claire, WI

Specific Tests and / or Properties Measured	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Inspection Contact	(16 x 18 x 14) in	$(209 + 1.2L) \mu\text{in}$	Coordinate Measuring Machie

[Return to Site listing \(top\)](#)

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

- Notes:
1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope
 2. The use of (R) signifies the Resolution of the unit under test, the use of (L) represents Length in inches, the use of (D) represents Diameter in inches.
 3. Uncertainties listed for Electromagnetic - DC/Low Frequency and RF/Microwave does not include possible contributions from a “best available” unit under test
 4. Derivatives of 10MHz will have different uncertainties due to resolution, noise, and gating errors.
 5. The tactile fit of an adjustable thread ring to a thread-setting plug is not a measurement of pitch diameter. The uncertainty for this pitch diameter setting is based on the contributors associated with the thread setting plug and environmental contributors only.
 6. The CMC for scales and balances are highly dependent upon the resolution of the unit under test. The uncertainties presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
 7. This scope is formatted as part of a single document including Certificate of Accreditation No. ACT-1265.



Jason Stine, Vice President